



Taipei,  
November 22, 2011

# ASIAA/CCMS/IAMS/NTU-Phys Joint Colloquia

*From STEM-EELS to multi-dimensional and  
multi-signal electron microscopy*

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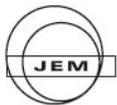
## Outline

**Signals, instrumentation and methods for STEM EELS**

**Atomically resolved elemental and bonding maps**

**Mapping plasmons and EM fields**

**When electrons and photons team up**



*Journal of Electron Microscopy* 60(Supplement 1): S161–S171 (2011)  
doi: 10.1093/jmicro/dfr028

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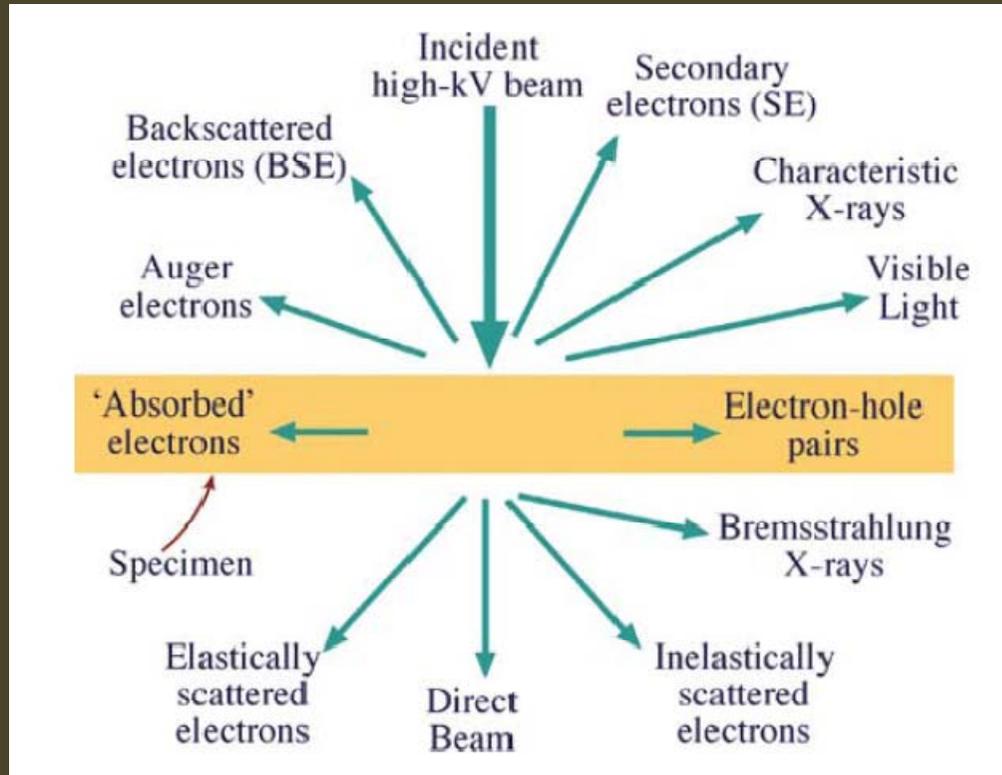
60th Anniversary Issue: Physical

**From electron energy-loss spectroscopy to  
multi-dimensional and multi-signal electron microscopy**

Christian Colliex\*

Laboratoire de Physique des Solides (UMR CNRS 8502), Université Paris Sud, Bldg. 510, 91405 Orsay, France

# Electron – Matter interactions



Secondary  
Event

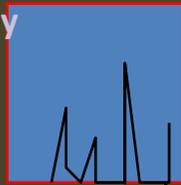
vs.

Primary Event

Transmission Electron Microscopy - A Textbook for Material Science  
David Williams and Barry Carter, Fig. 1.3, page 7.

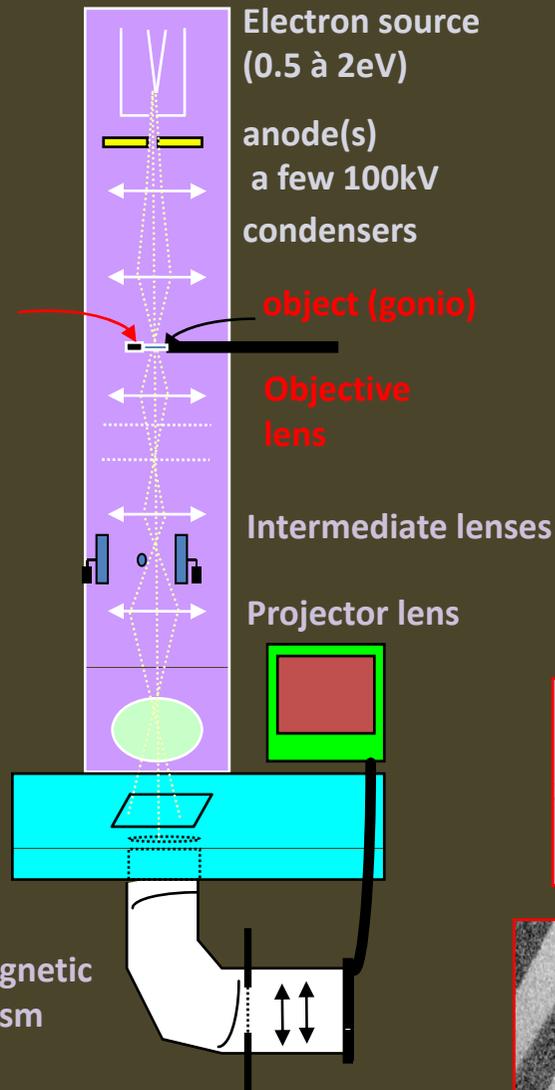
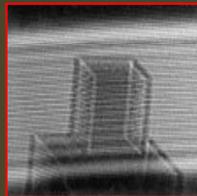
# Working modes for an transmission electron microscope

EDX spectroscopy



Nanolaboratory :  
Specific specimen  
holders and stages

Hologram



Electron source  
(0.5 à 2eV)

anode(s)  
a few 100kV  
condensers

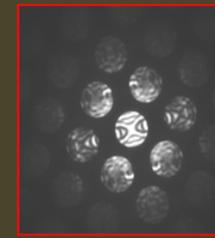
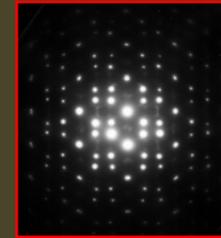
object (gonio)

Objective  
lens

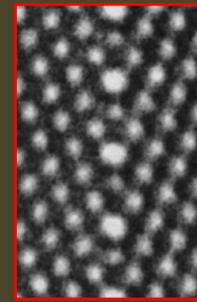
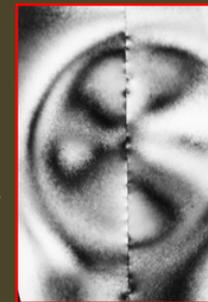
Intermediate lenses

Projector lens

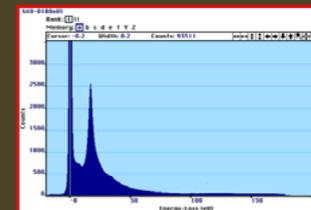
Magnetic  
prism



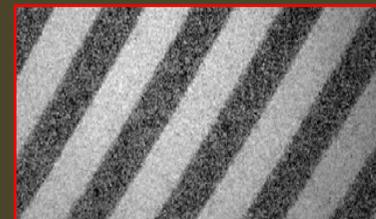
Diffractions



HREM  
imaging



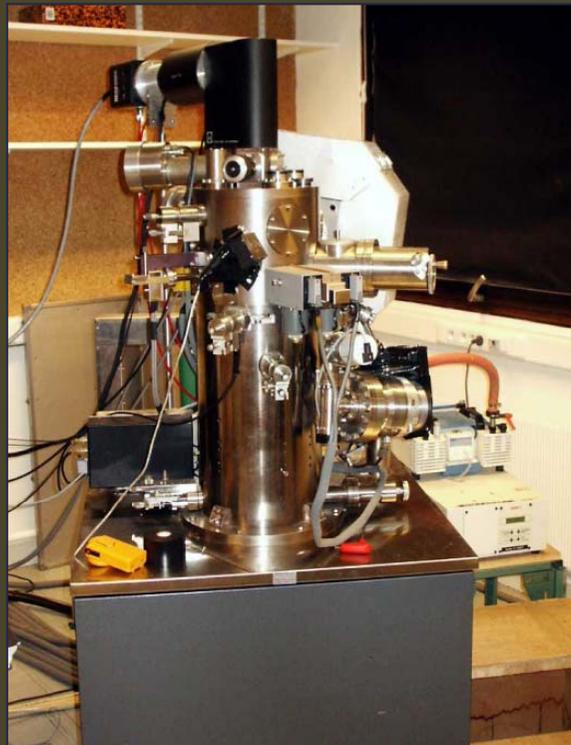
Electron Energy Loss  
Spectroscopy  
(EELS)



Energy filtered imaging

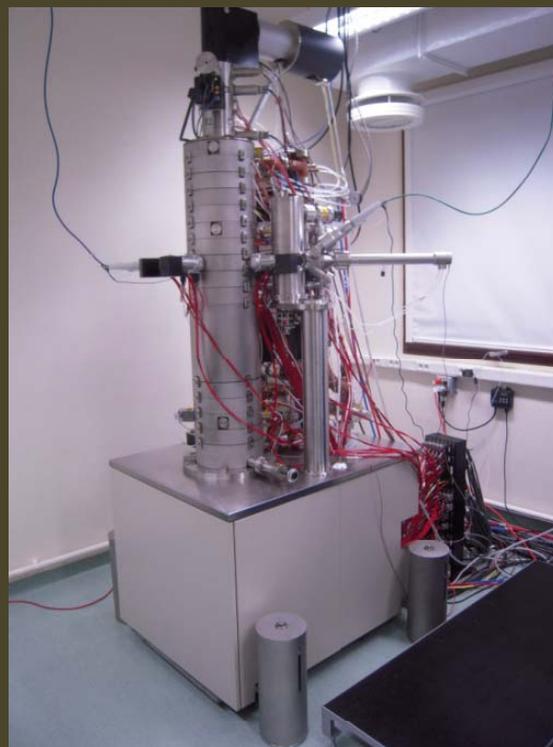
# STEMs with EELS analysers at Orsay

1980 - 20xx



VG HB 501

2008 - 2011



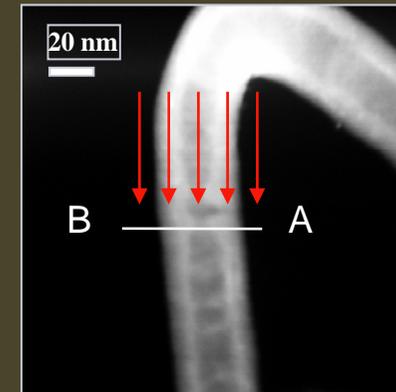
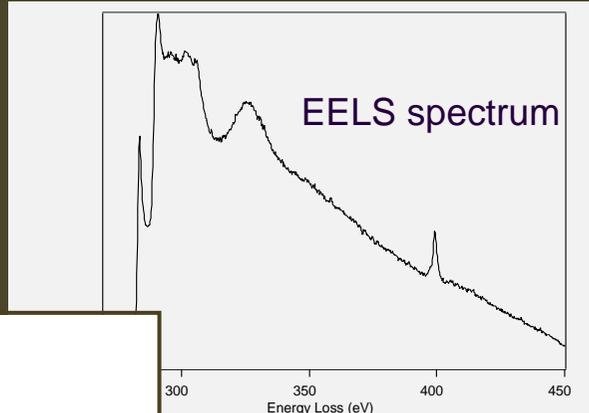
NION UltraSTEM 100

2011 - 20xx



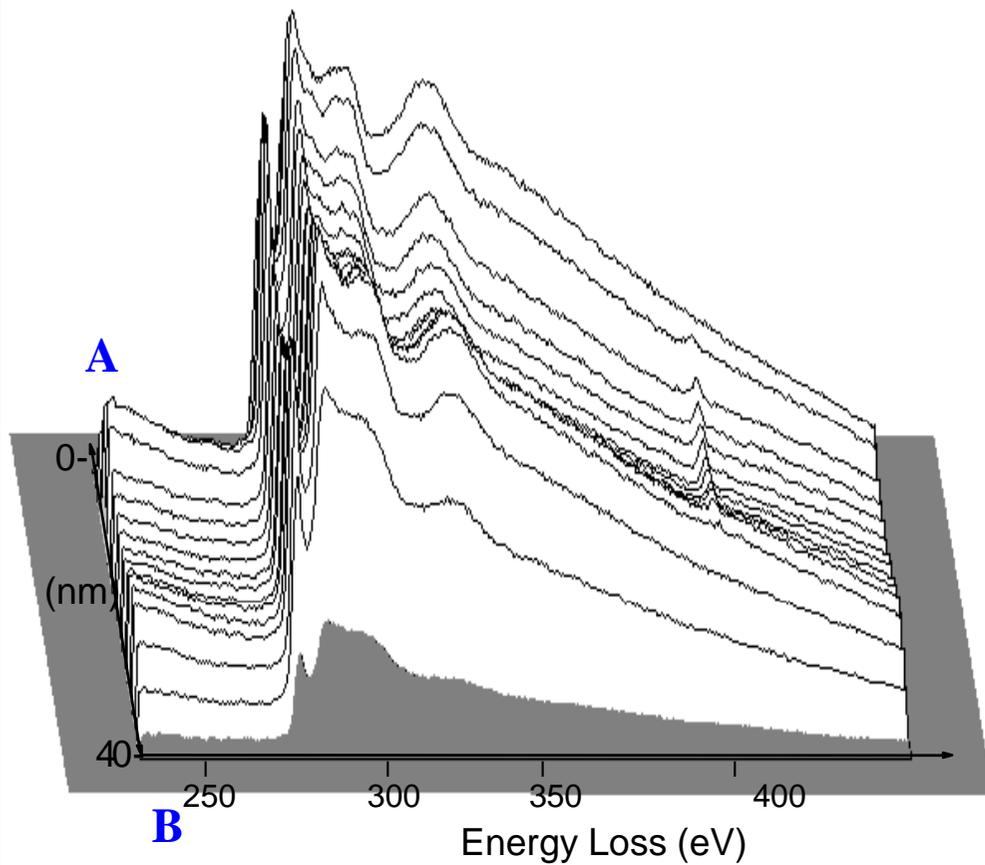
NION UltraSTEM 200

# EELS spectrum-image at Orsay



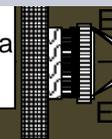
HADF image

## SPECTRUM LINE



Spectrum 0.5 to 0.8 eV  
1 ms to 5 s

Camera  
CCD



Magnetic spectrometer

HADF  
detectors

Specimen

Probe

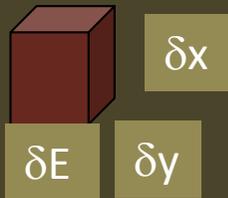
- 0.1 to 1 nA
- in 0.5 to 1 nm

Scanning coils

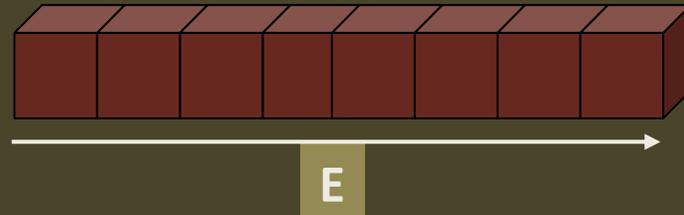
100 keV

Field emission gun

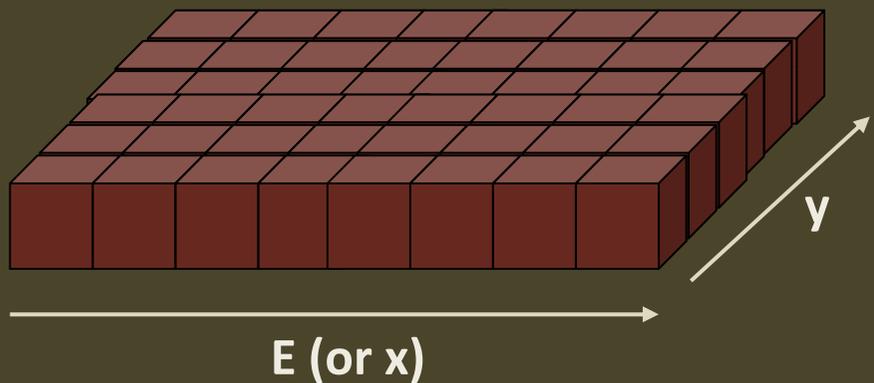
# Multi-dimensional microscopy in a composite space ( $x, y$ position, $E$ energy and $t$ time)



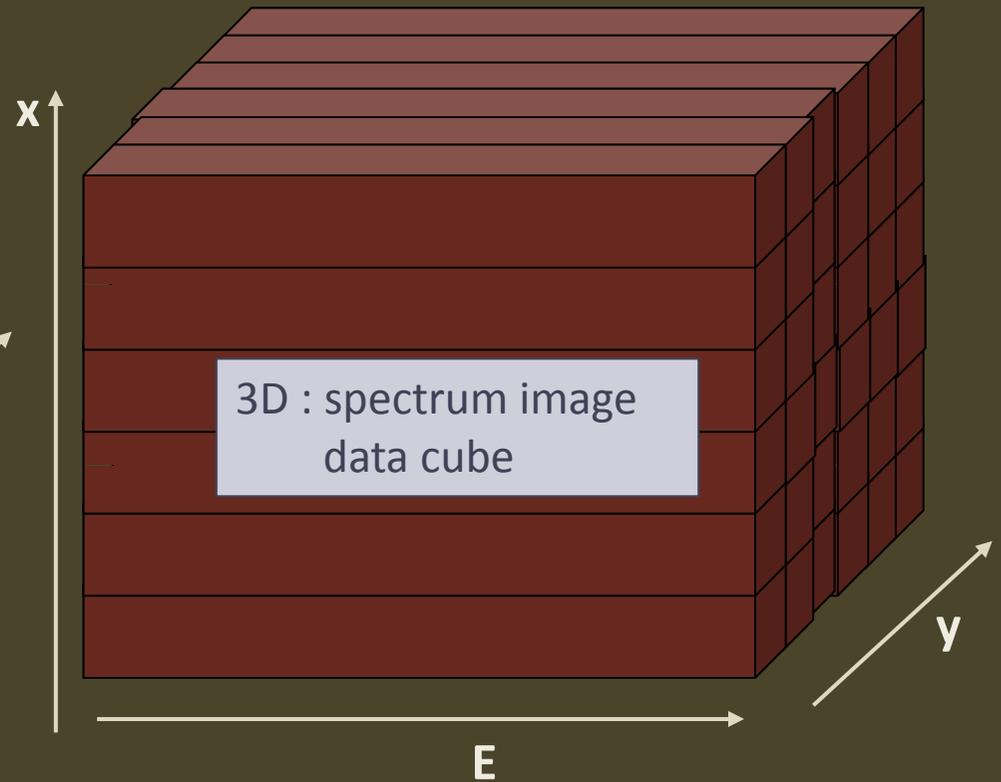
0D : bit of information



1D : EELS spectrum



2D : spectrum line  
or E- filtered image



3D : spectrum image  
data cube

# An electron microscope for the aberration-corrected era

O.L. Krivanek\*, G.J. Corbin, N. Dellby, B.F. Elston, R.J. Keyse, M.F. Murfitt,  
C.S. Own, Z.S. Szilagy, J.W. Woodruff

Nion Co., 1102 8th Street, Kirkland, WA 98033, USA

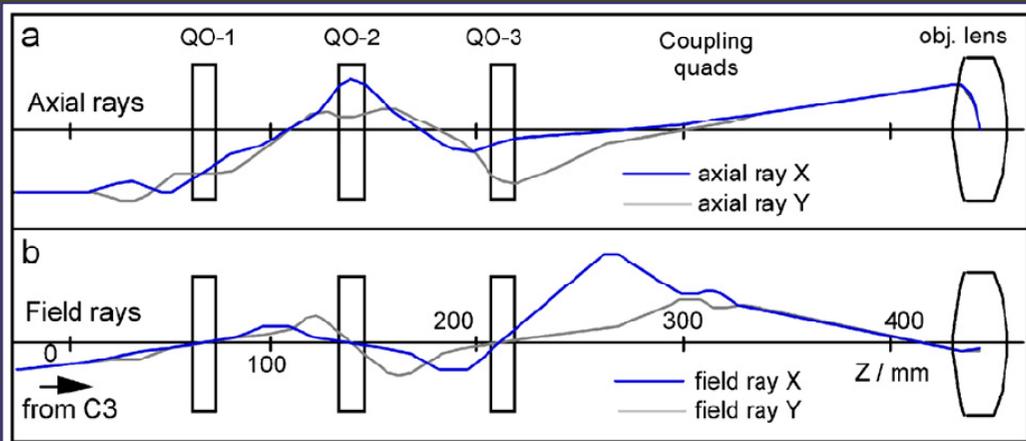
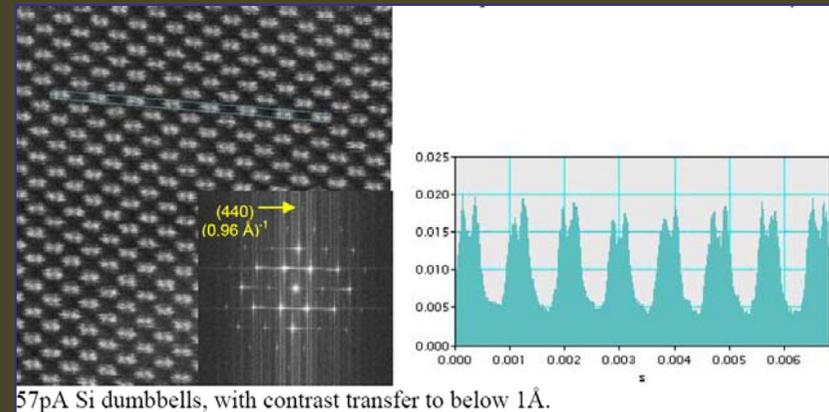
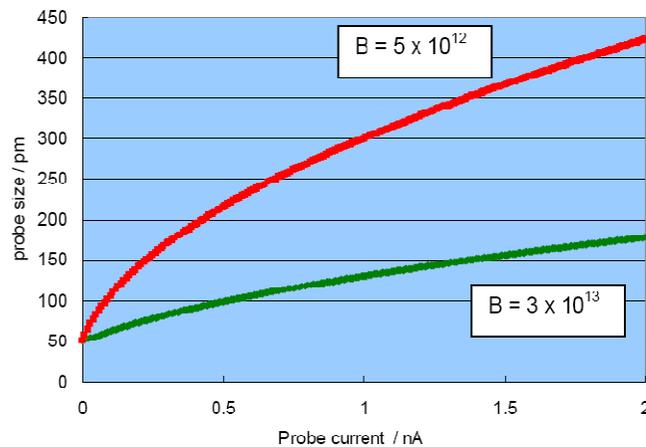


Fig. 3. Axial (a) and field (b) trajectories through the  $C_3/C_5$  corrector.

Use of  $C_s$  correctors to reduce probe size or to increase probe current :

- i)  $<1 \text{ \AA}$  probe size at 100 kV,
- $<0.7 \text{ \AA}$  at 200 kV
- ii) 200 pA of current in a  $1.4 \text{ \AA}$  probe
- iii) 1 nA current in a  $2.3 \text{ \AA}$  probe

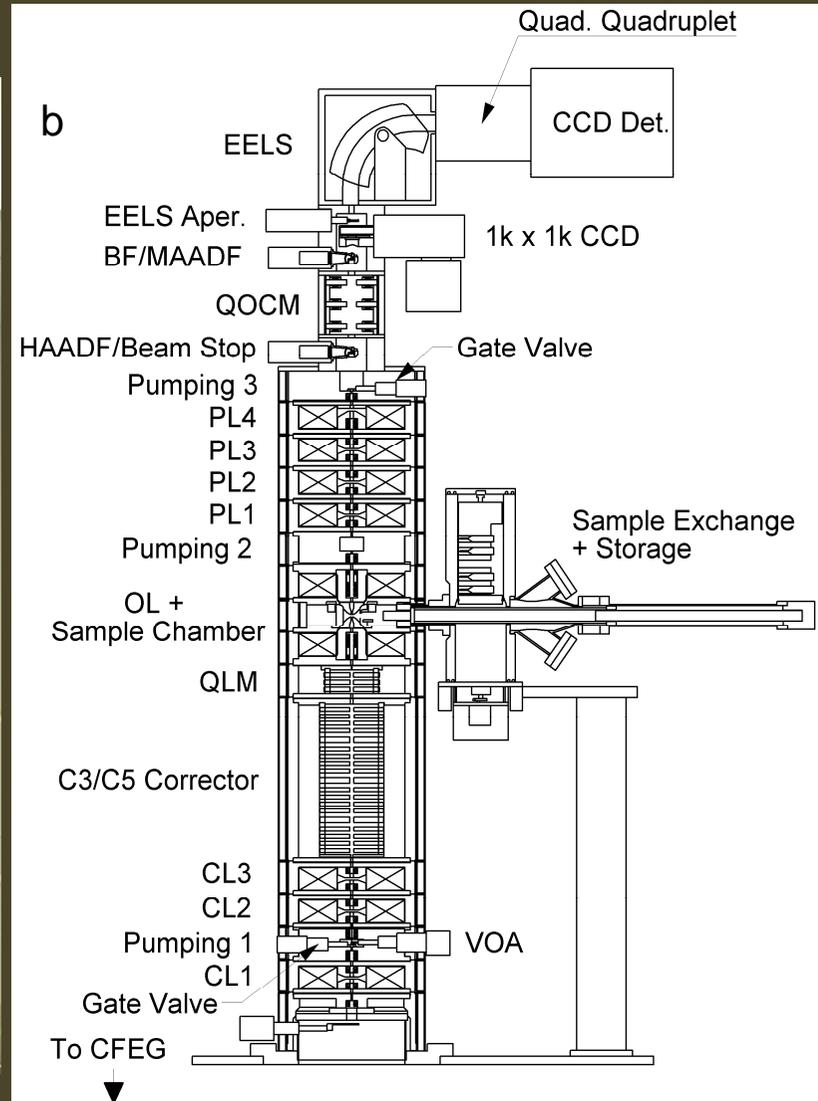
Fig. 6. The theoretical probe size of a 200 kV  $C_3/C_5$  corrected STEM giving an aberration-limited probe of 50 pm FWHM, as a function of the probe current for two different brightnesses.  $B = 3 \times 10^{13} \text{ A / (m}^2 \text{ sr)}$  is representative of CFE systems,  $B = 5 \times 10^{12} \text{ A / (m}^2 \text{ sr)}$  is representative of Schottky systems [14] (at 200 kV).



57pA Si dumbbells, with contrast transfer to below  $1 \text{ \AA}$ .

Orsay Nion U-STEM 100 acceptance tests

# New UltraSTEM for aberration-corrected nanoanalysis (delivered in Orsay in 2008)



The column is built from modules that all have the same mechanical interface and are 100% interchangeable.

Each module has triple magnetic plus acoustic shielding.

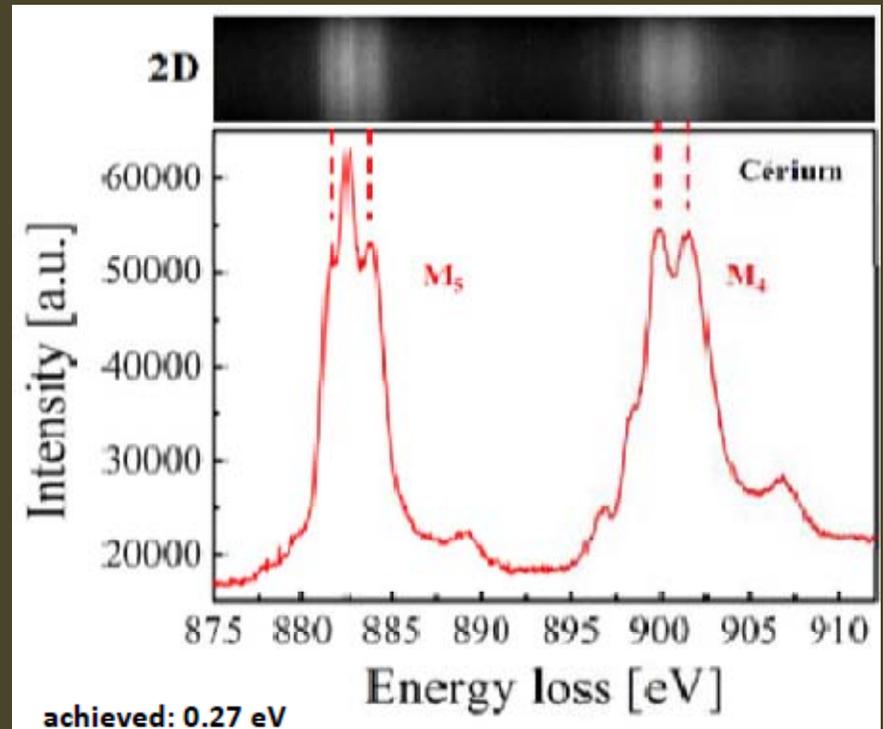
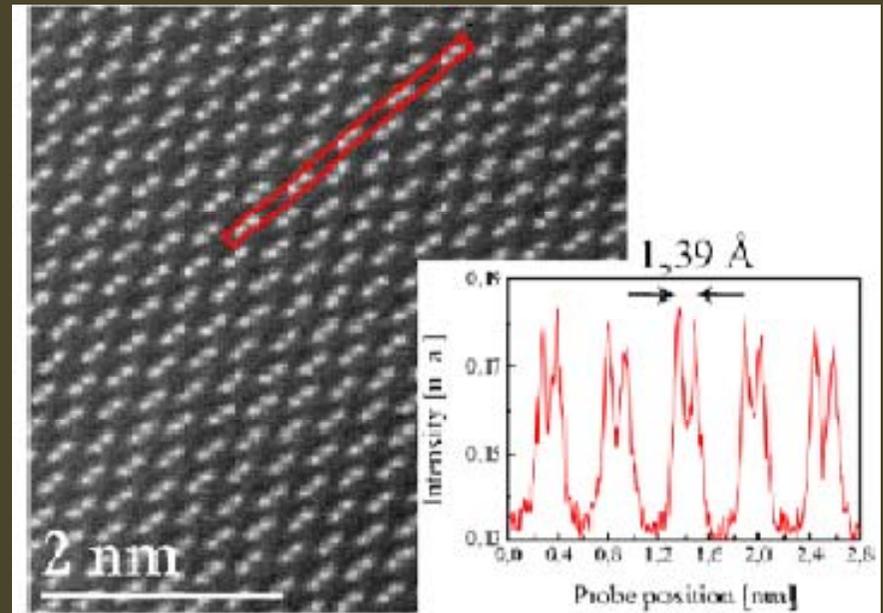
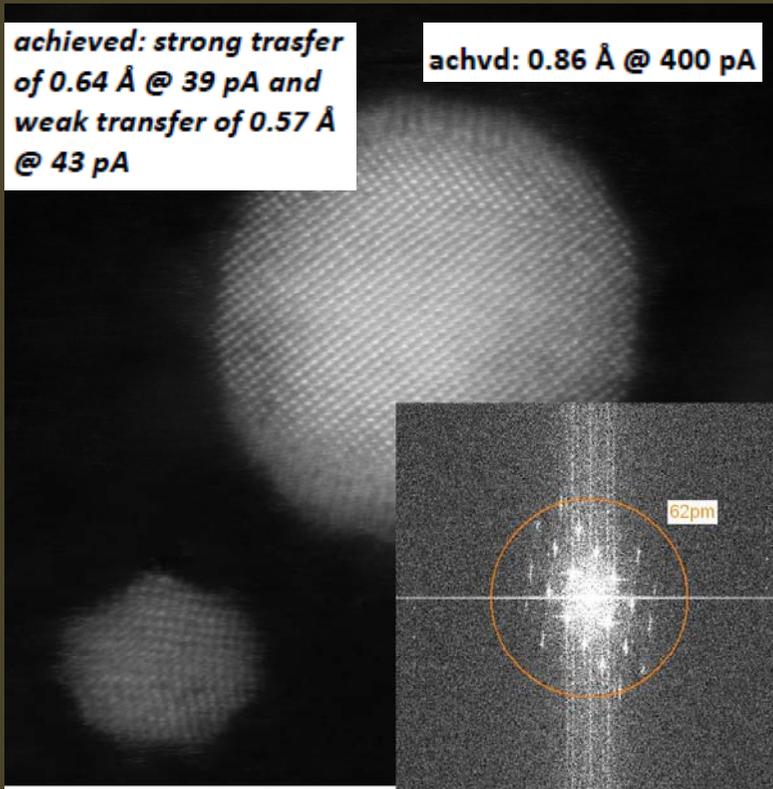
Emphasis is on small probe formation and efficient coupling into detectors.

Everything including sample exchange can be operated remotely.

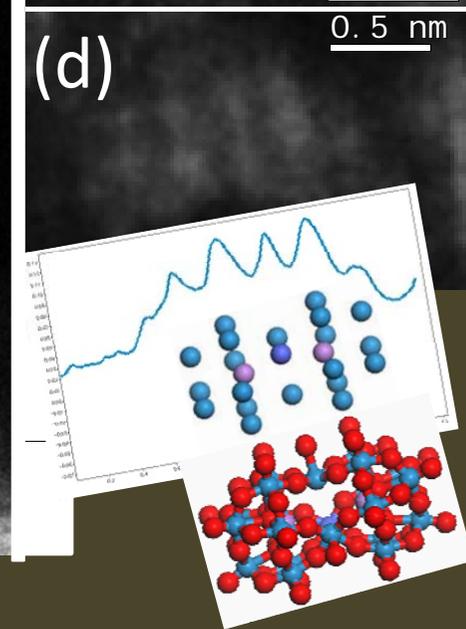
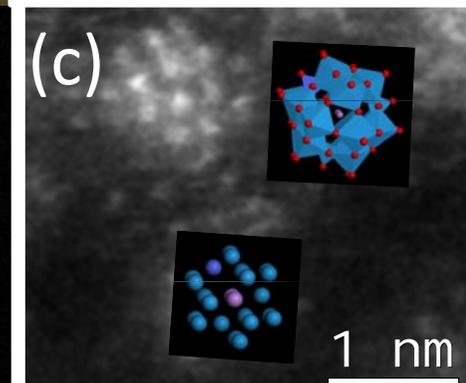
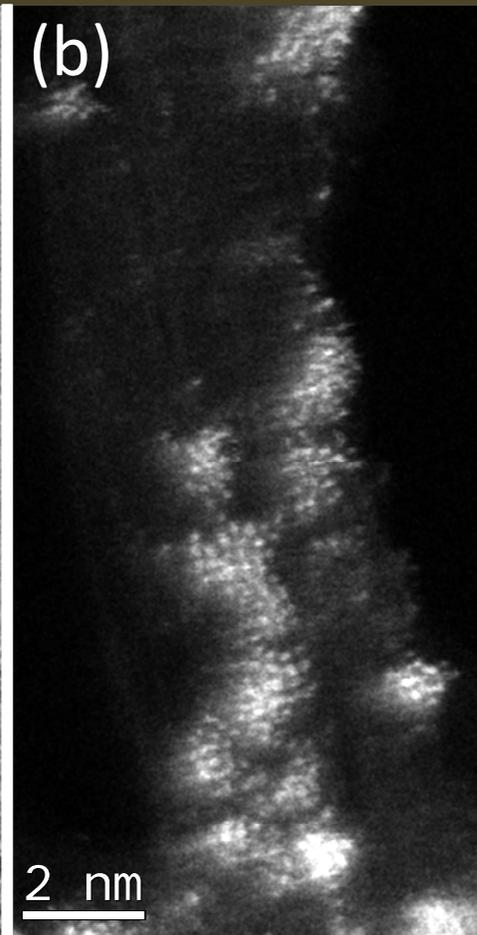
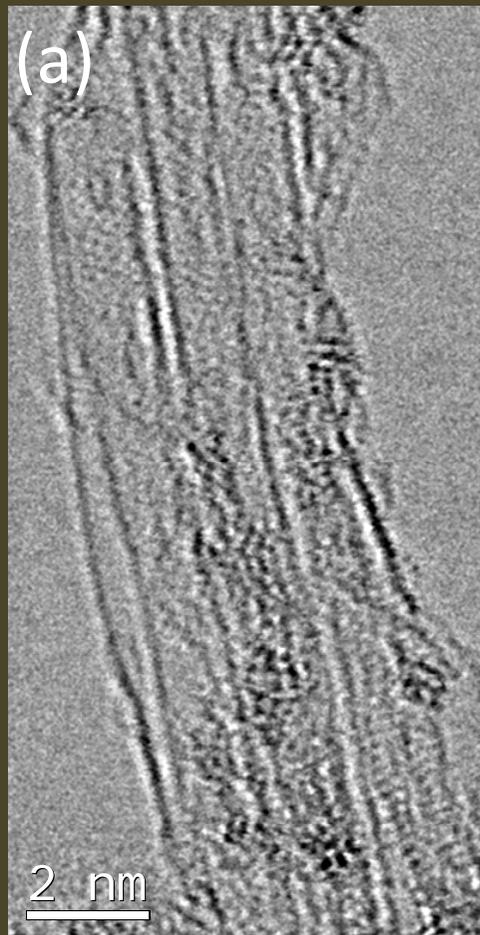
# Nion UltraSTEM 200 performance at Orsay

achieved: strong transfer  
of 0.64 Å @ 39 pA and  
weak transfer of 0.57 Å  
@ 43 pA

achvd: 0.86 Å @ 400 pA



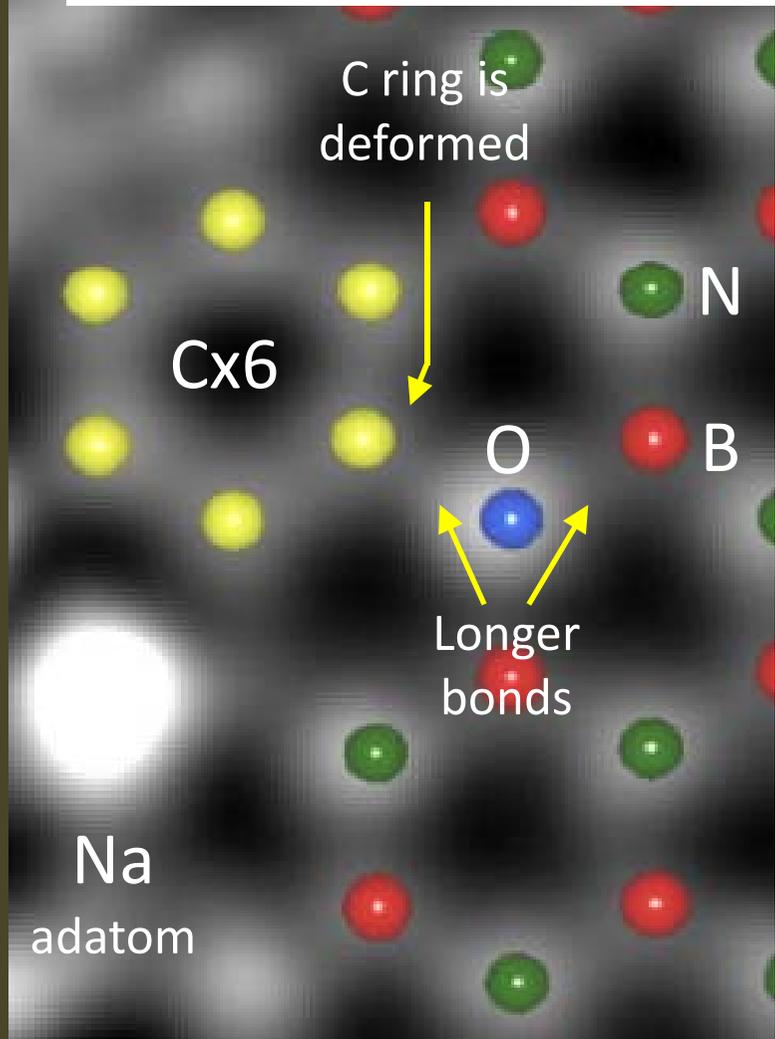
# Imaging molecules containing heavy atoms



polyoxometalate (POM;  $\text{As}_2\text{W}_{20}\text{O}_{70}\text{Co}(\text{H}_2\text{O})$ ) molecules grafted on C-SWNT  
courtesy A. Gloter, Orsay (2011)

# BN monolayer with i

Result of DFT calculation overlaid



nature 464, 457-660 25 March 2010

www.nature.com/nature

Insight Ageing

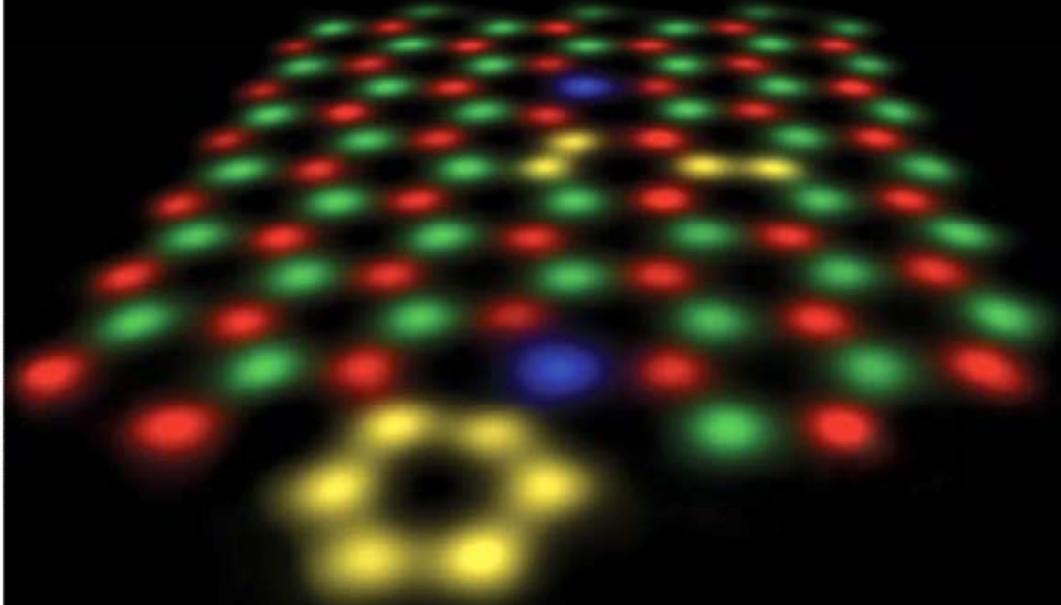
na2288 npi

NATURE INSIGHT AGEING

25 March 2010 | www.nature.com/nature | £10

THE INTERNATIONAL WEEKLY JOURNAL OF SCIENCE

# nature



## ATOM-BY-ATOM ANALYSIS

Elements mapped by annular dark field electron microscopy

**MEASURING SCIENCE**  
Rethinking a flawed system

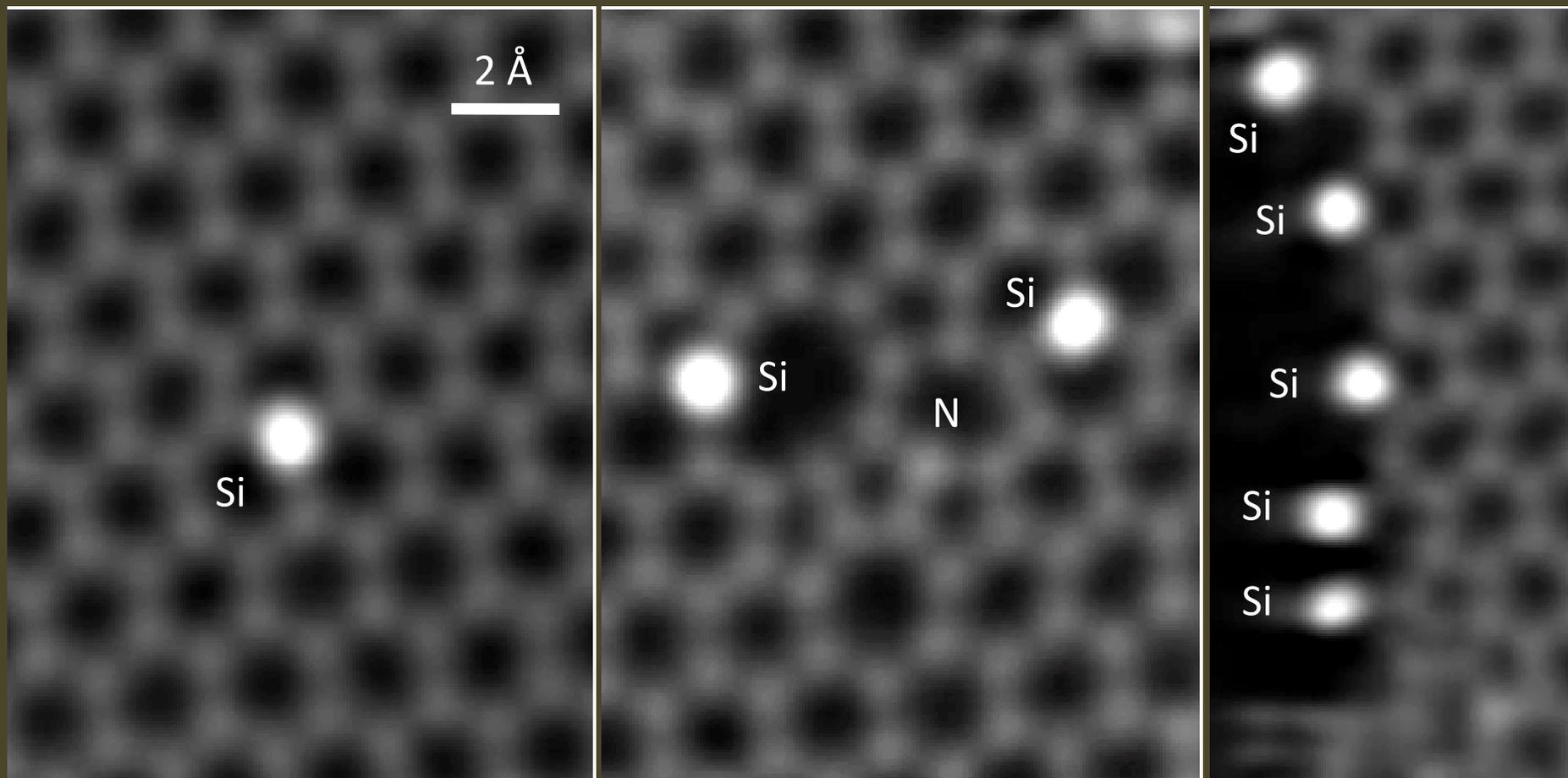
**SIRTUIN ACTIVATORS**  
Can they delay ageing?

**CORONARY ARTERIES**  
Vein hope for bypass grafts

**NATUREJOBS**  
Spotlight on  
Indiana



## Si substituting for C in monolayer graphene



**Si in topologically  
correct graphene**

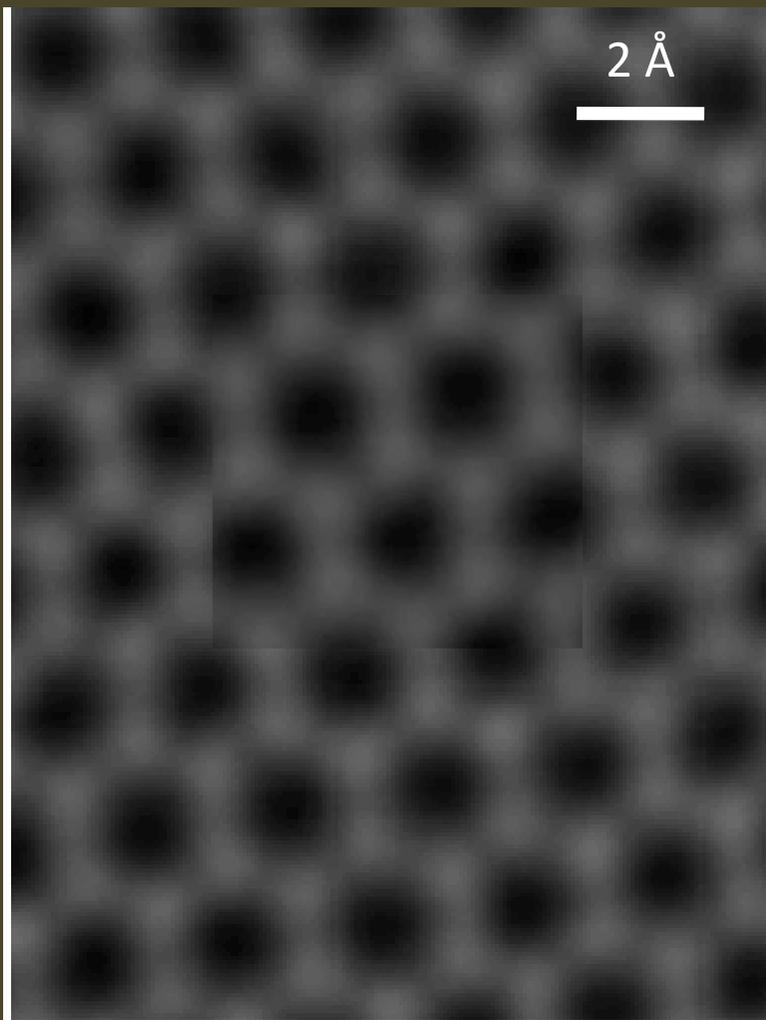
**Si at and near  
topological defects**

**Si at graphene's  
edge**

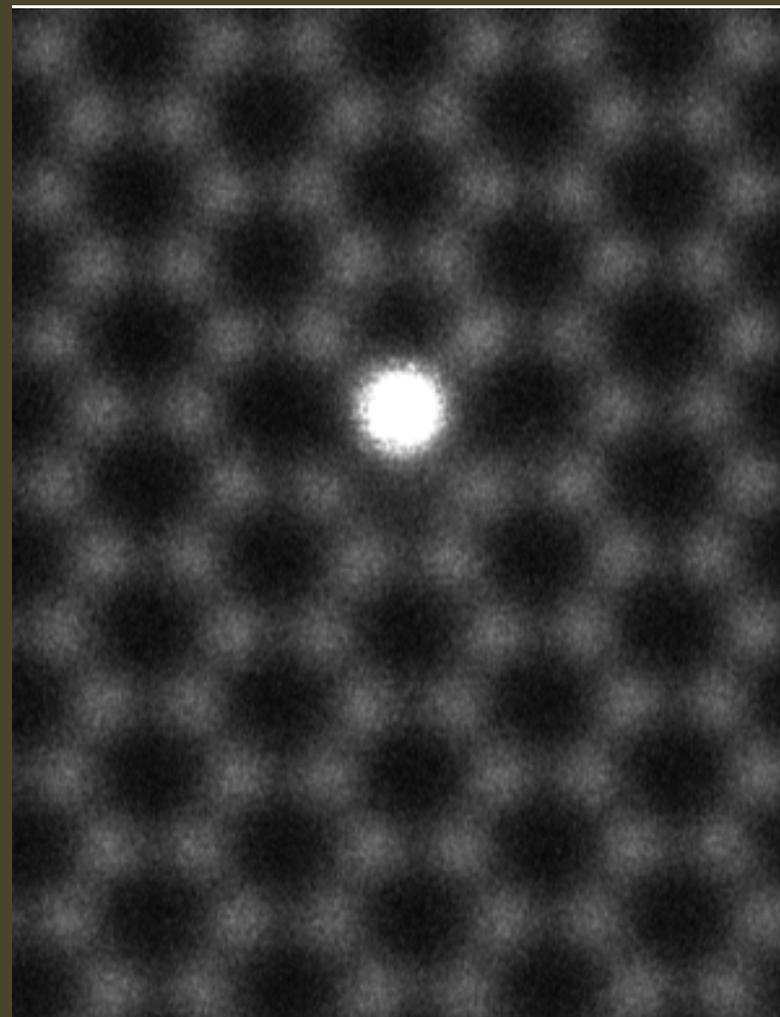
Medium angle annular dark field (MAADF) images.

Nion UltraSTEM100 at ORNL, 60 kV. Image courtesy Matt Chisholm, ORNL,  
sample courtesy Venna Krisnan and Gerd Duscher, U. of Tennessee.

## Si substituting for C: 2 structures are possible



Si in defect-free graphene strains (and buckles) the foil.  
(courtesy Matt Chisholm)



Si in defective, but less strained graphene is more stable. (15 images added together, no other processing, courtesy Juan-Carlos Idrobo)

# EELS spectroscopy : spectral domains

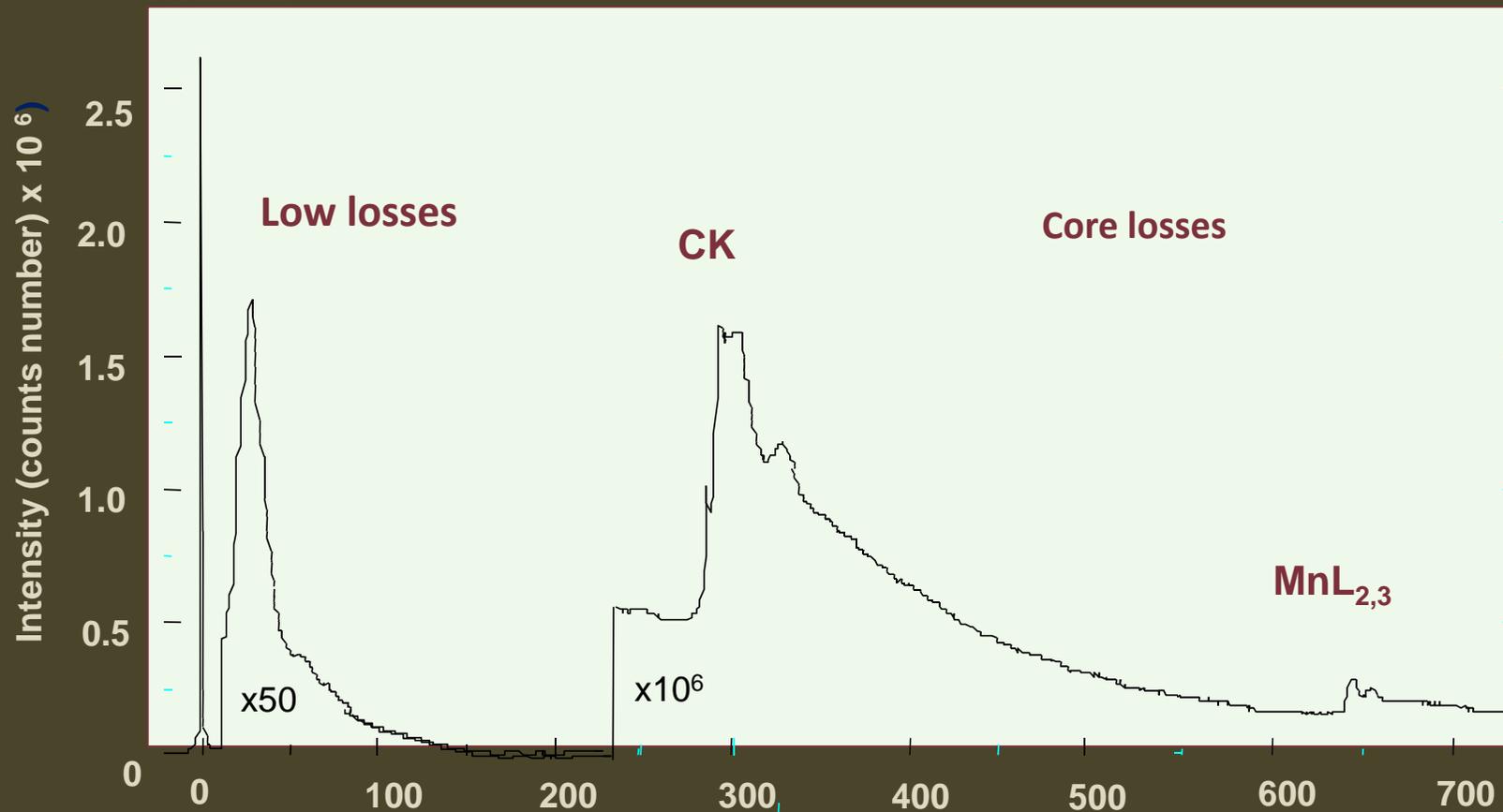
Phonons

Plasmons

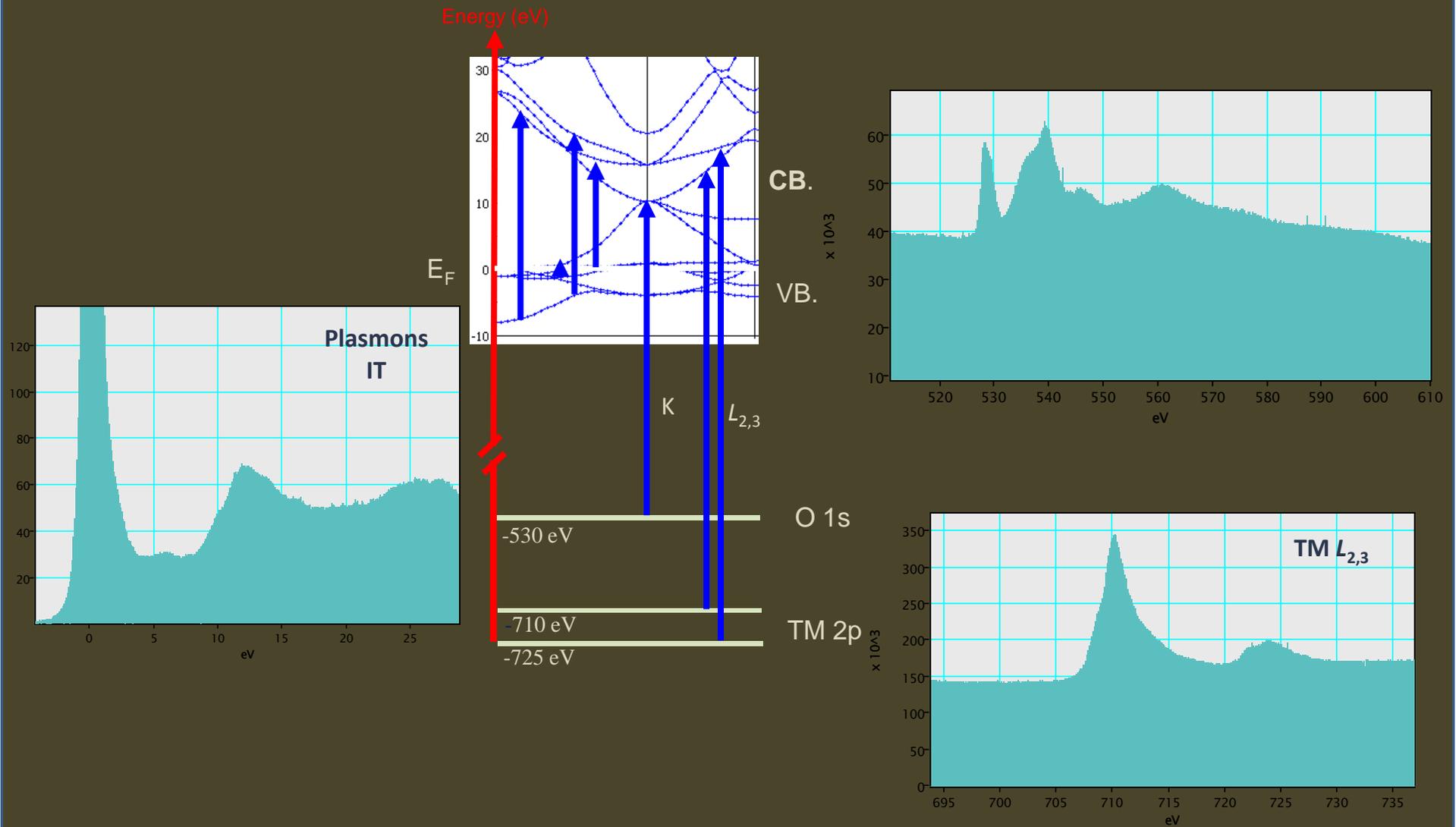
Absorption edges

IR  
UV  
visible

X



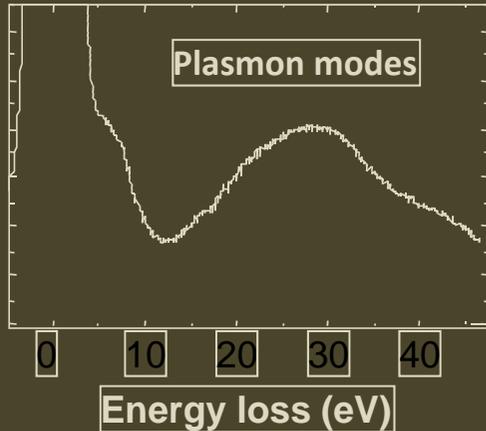
# EELS: Involved electron populations and associated transitions



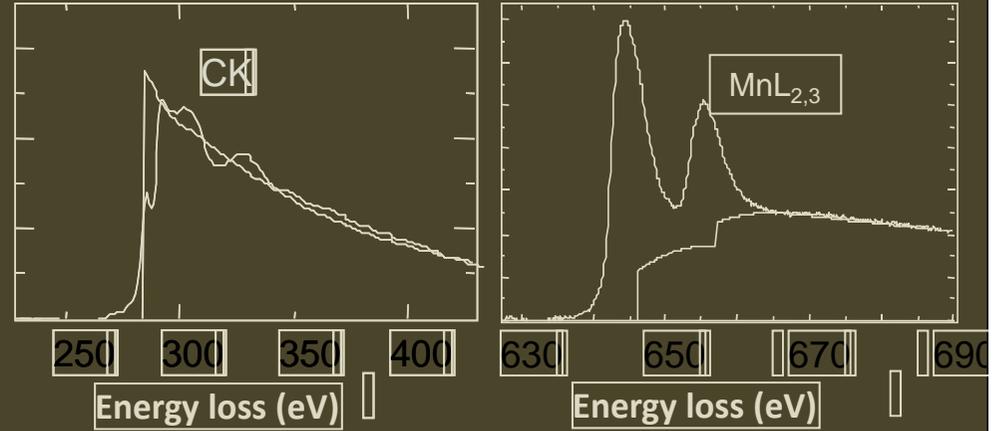
EELS gives informations on the electronic structure

# EELS spectroscopy : spectral domains

## Low energy-loss domain



## Core energy-loss domain



Map different physical parameters, electronic, optical or magnetic, which are especially important for electronic industries

Requires instruments adapted to measure the properties of interest at the relevant scale



Towards

In all cases, develop the theory for interpreting spectroscopical data, i.e. a physics of excited states

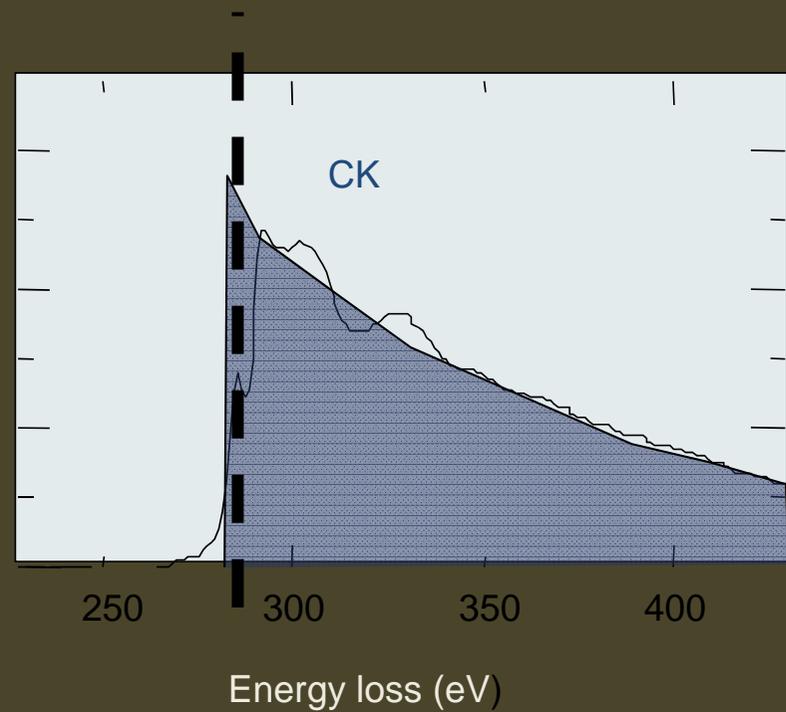
Map with high accuracy the nature, the position and bonding of the atoms responsible for the structural properties of real materials (defects, interfaces, nanomaterials)

Requires instruments with best spatial and energy resolutions (0.1 eV)

## Absorption edges domain : three types of information

→ Identification of elements

→ Elementary quantification



→ Study of the unoccupied electron states distribution

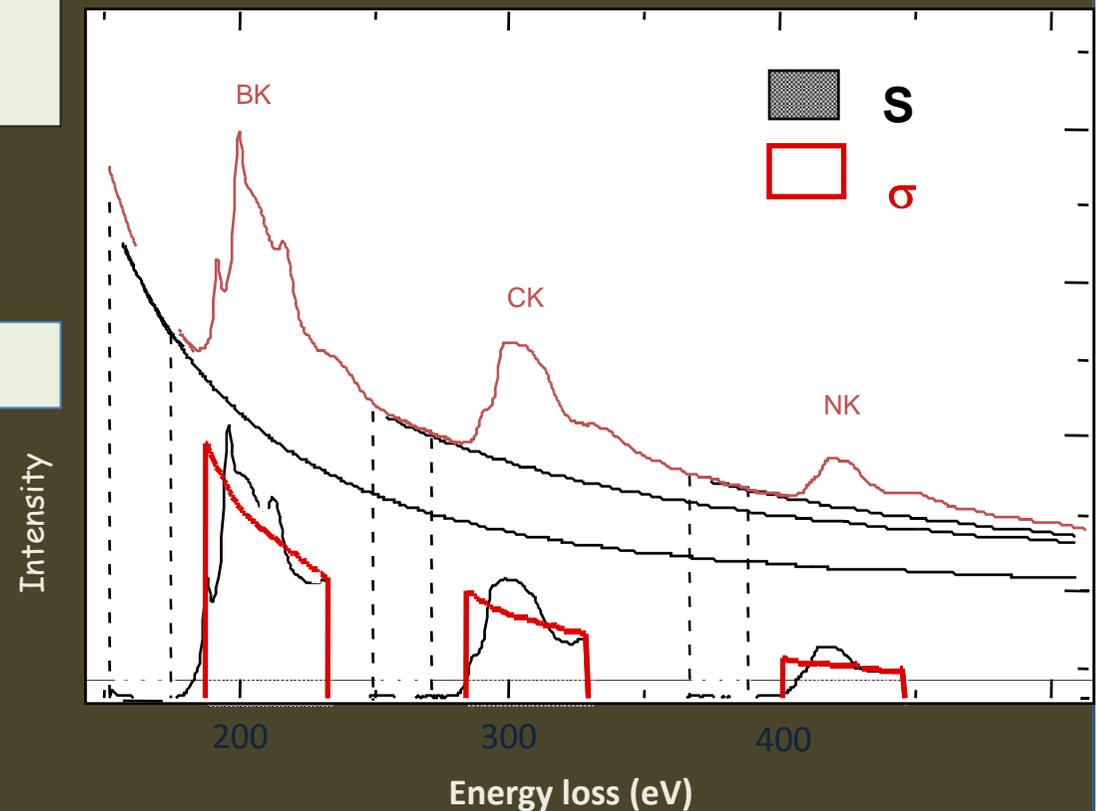
# Quantitative elemental analysis

Characteristic signal : proportional to the number of atoms per unit area for the element detected in the analysed area

$$S = ct. I N \sigma$$

Atomic concentration ratios:

$$\frac{N_A}{N_B} = \frac{S_A}{S_B} \times \frac{\sigma_B}{\sigma_A}$$



**EELS core-level spectroscopy:  
elemental and bonding maps with atomic  
resolution**

- 1. Individual atoms**
- 2. Crystalline structures and interfaces**
- 3. Application to Tunnel ElectroMagneto  
Resistance – TEMR**

## Single atom identification (signal/noise criteria)

Peapods :

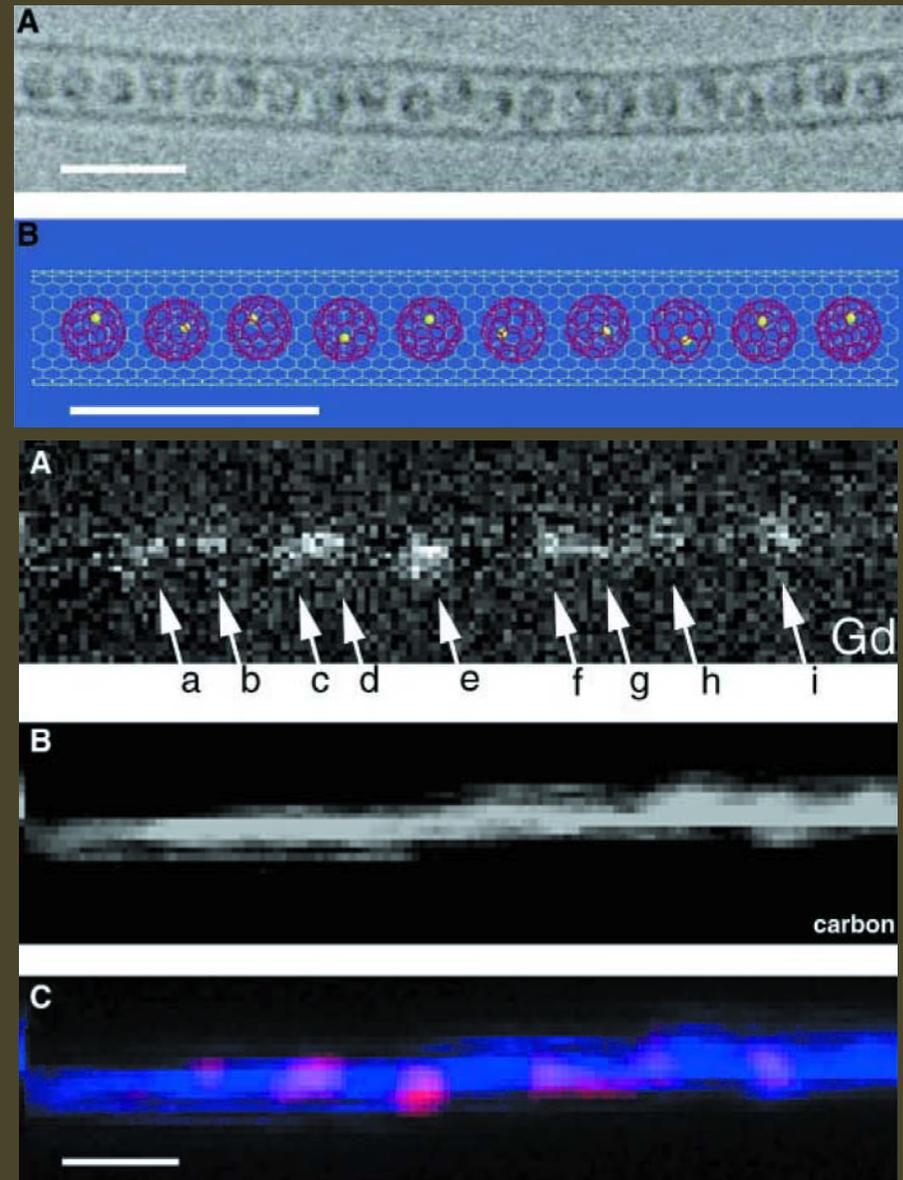
[Gd@C<sub>82</sub>@SWCNT](#)

Element selective single-atom imaging

A : HREM image

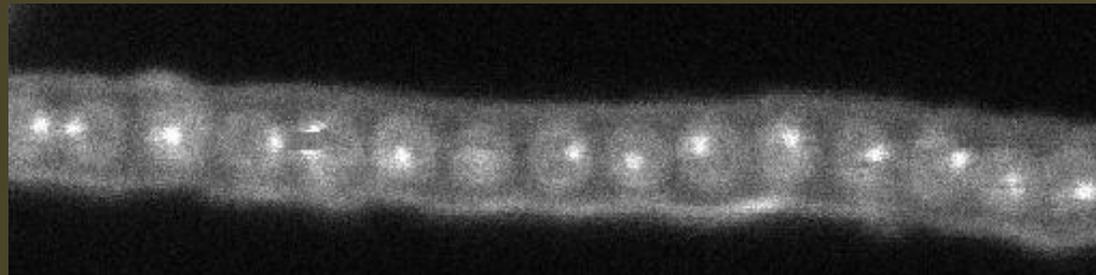
B : Schematic presentation

C : Superposed maps of the Gd N45 and C K signals extracted from a 32x128 pixels spectrum-image (C in blue, Gd in red)

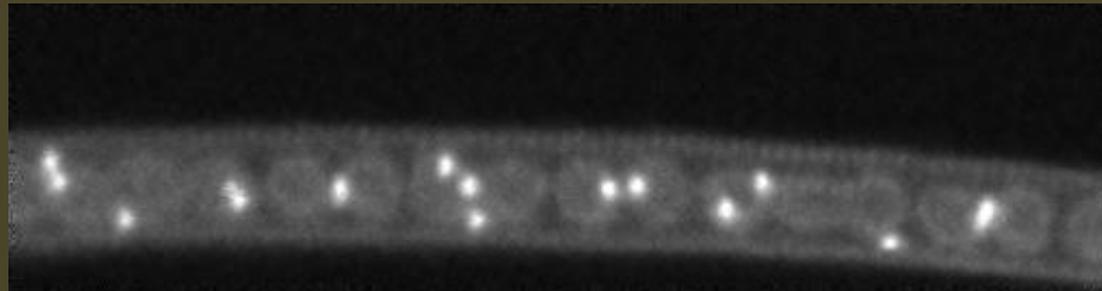


K. Suenaga et al., Science (2000)

# STEM imaging of peapods at 30 and 60 kV with Delta corrector



30kV

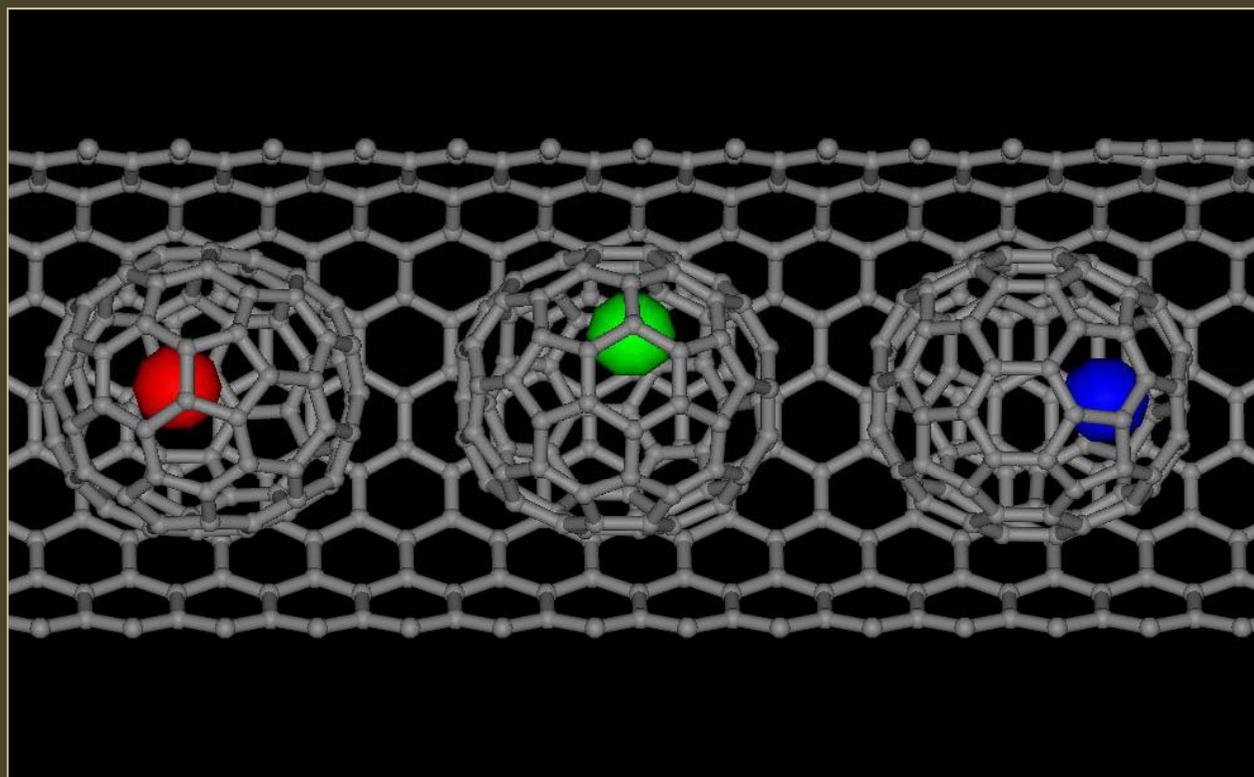


60kV

**Damage drastically reduced at 30kV**

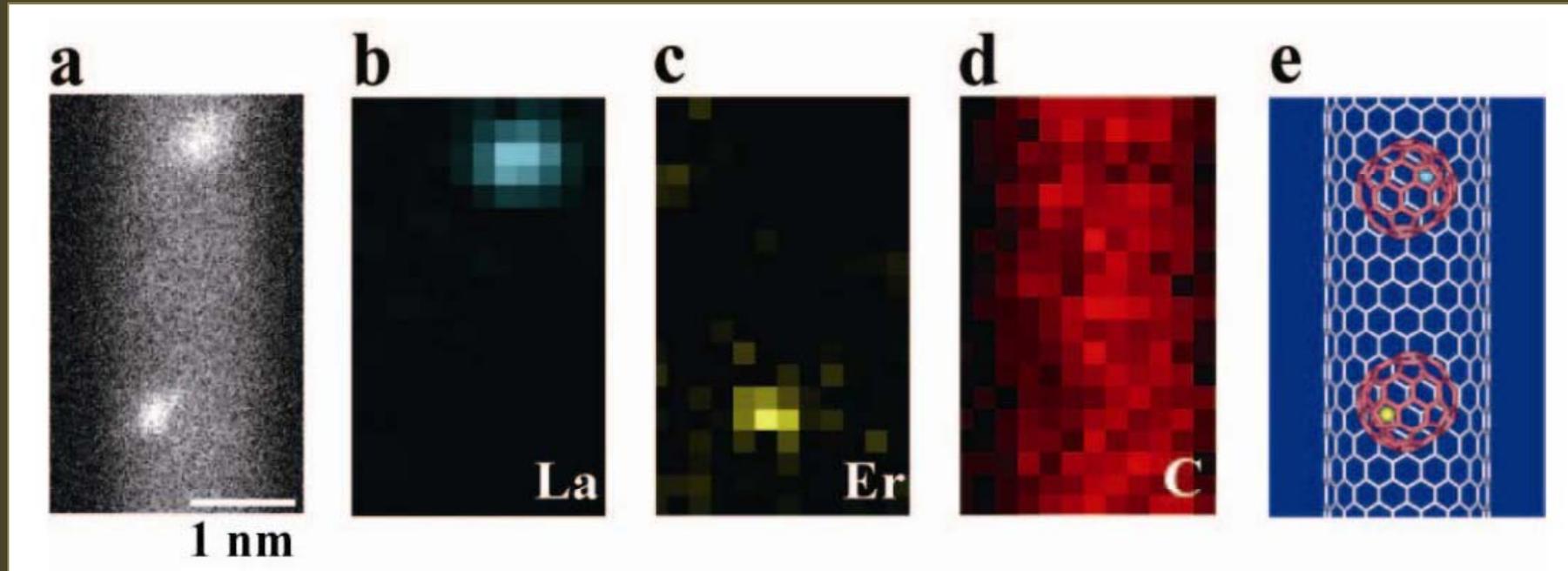
**Courtesy Suenaga, Sawada & Sasaki (2010)**

Single atom imaging by STEM-EELS at low voltage with the  
delta corrector



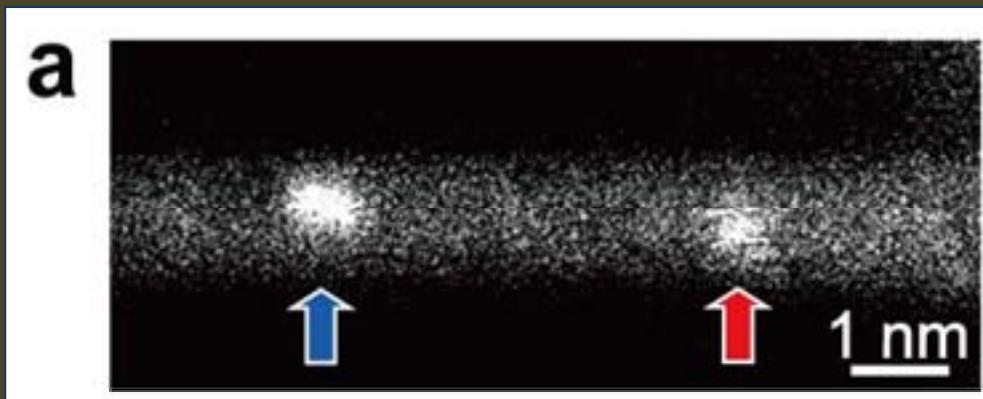
Endohedral fullerenes  
M@C82 (M= La, Ce, Er)  
Iizumi and Okazaki

## Atom by atom labeling at 60kV



Courtesy K. Suenaga (AIST, Tsukuba, 2010)

# Valence state identification of individual atoms

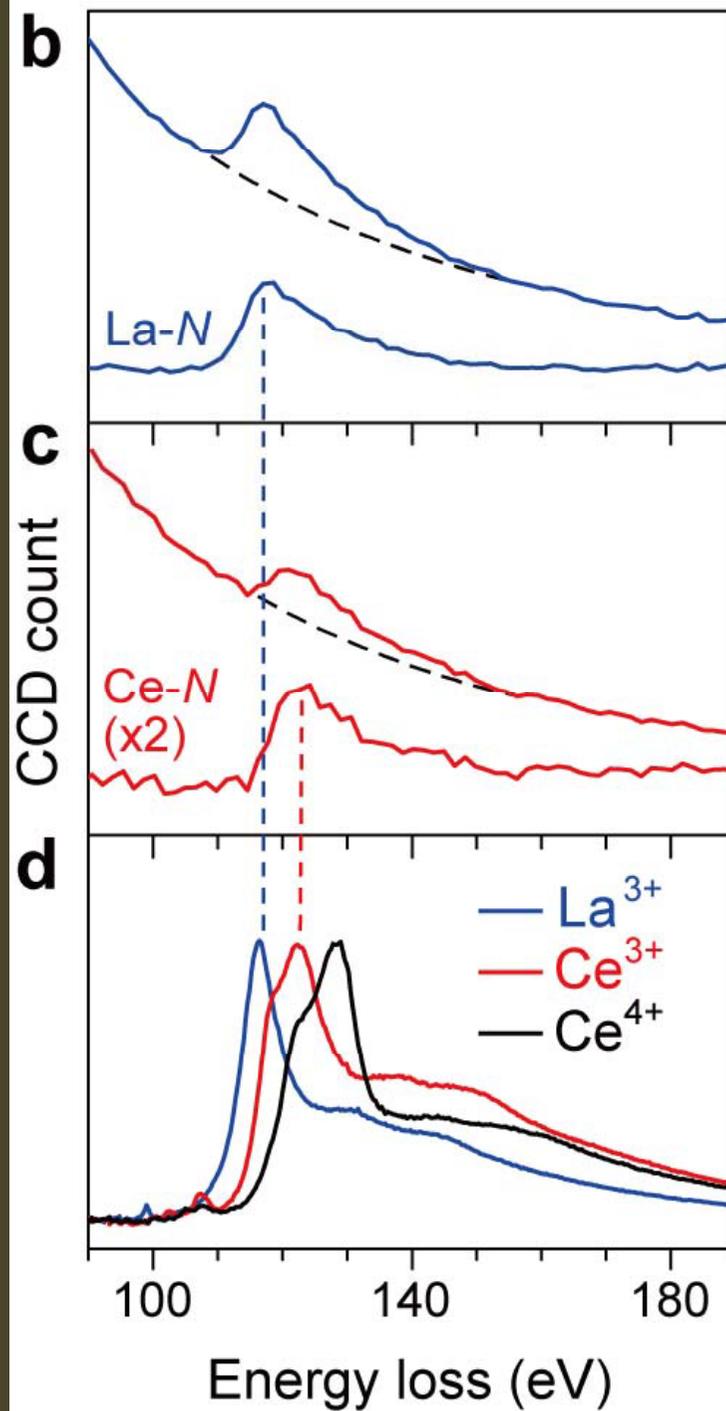


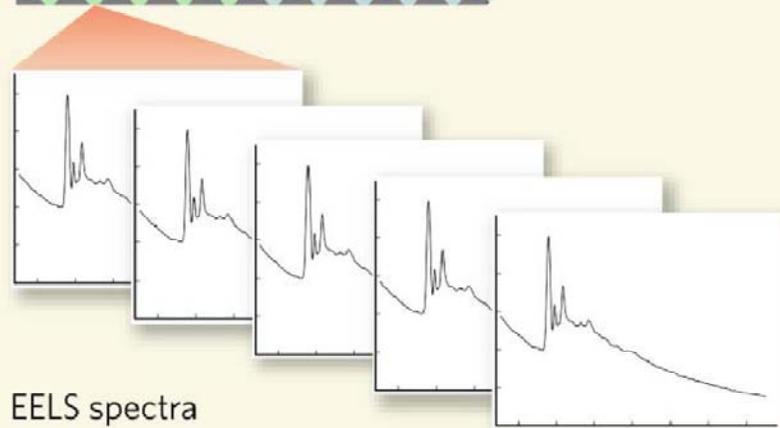
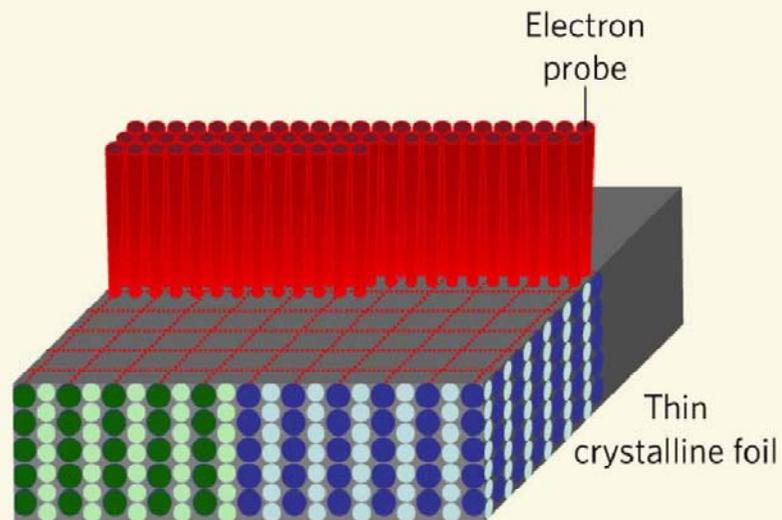
La<sup>3+</sup>

Ce<sup>3+</sup>

La<sup>3+</sup> in LaCl<sub>3</sub>  
Ce<sup>3+</sup> in CeCl<sub>3</sub>  
Ce<sup>4+</sup> in CeO<sub>2</sub>

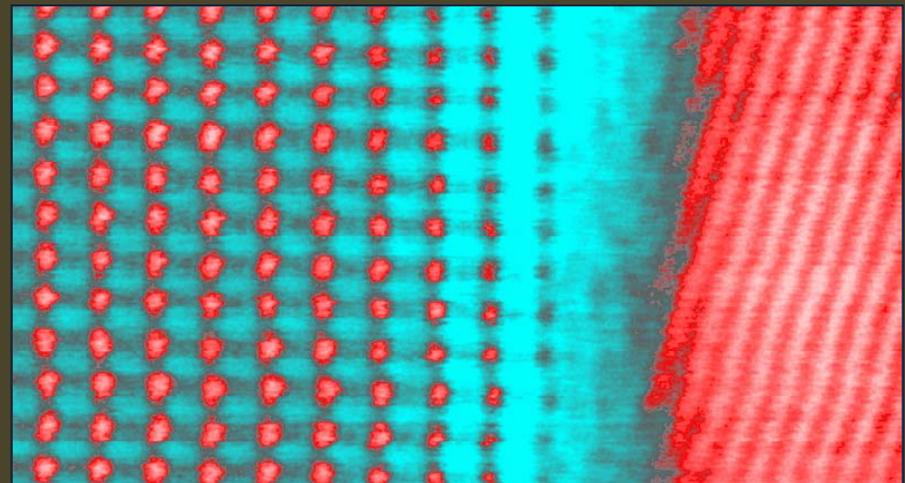
Courtesy K. Suenaga (AIST, Tsukuba, 2010)





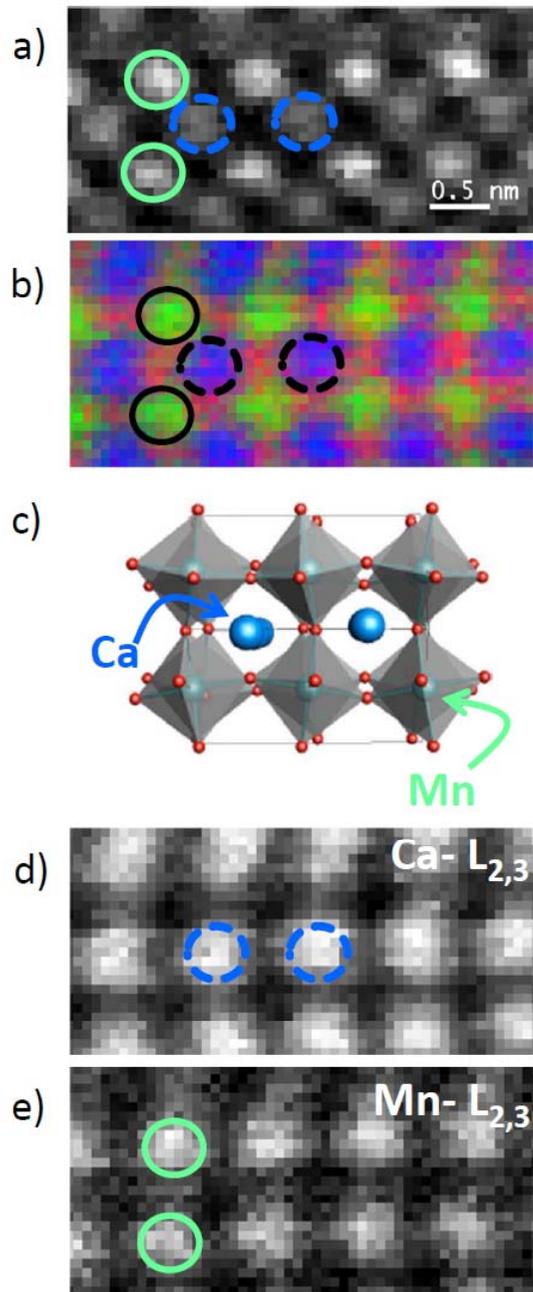
## EELS spectrum-imaging across interfaces

See C. Colliex, Nature N&V (2007)

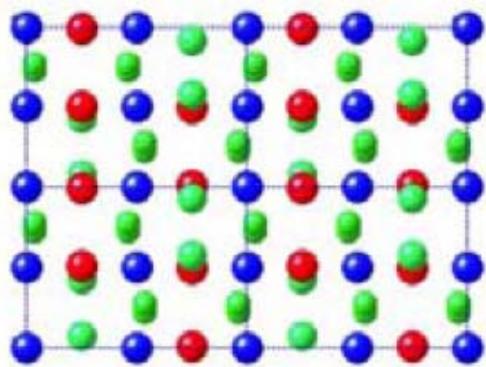


HAADF micrograph

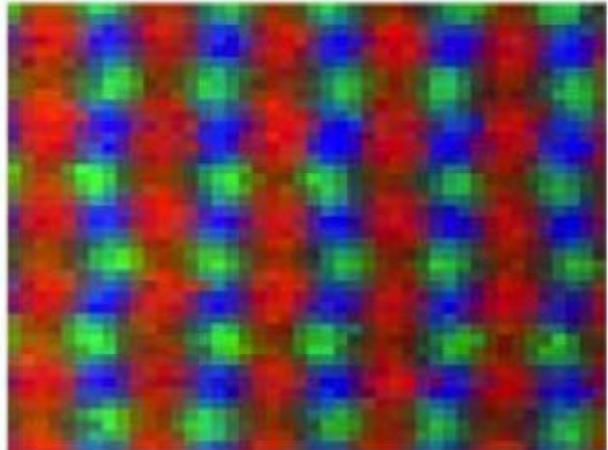
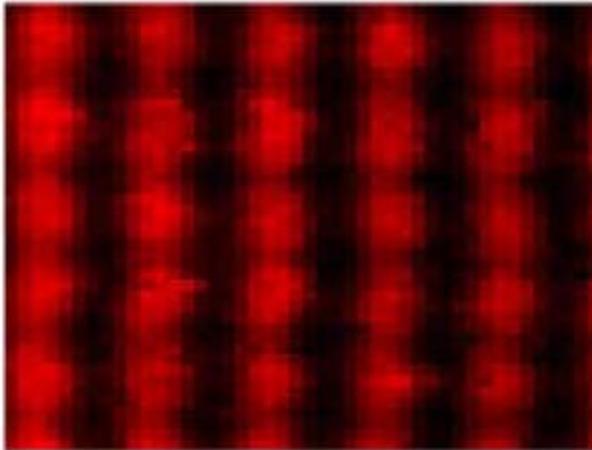
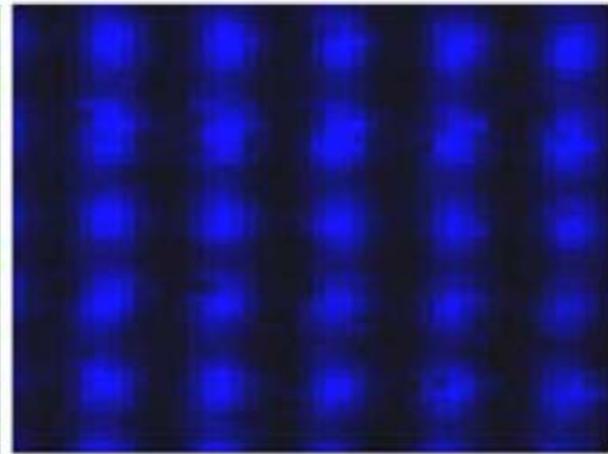
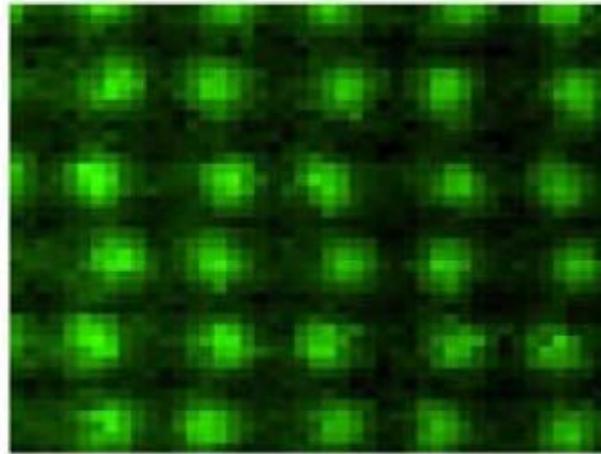
## Elemental maps recorded with NION UltraSTEM at Orsay (courtesy Laura Bocher, 2011)



a) Atomically-resolved STEM-HAADF of  $\text{CaMn}_{0.92}\text{Nb}_{0.08}\text{O}_3$  perovskite-type oxide oriented along the pseudocubic [100] zone axis, b) the false color reconstructed elemental map combining the O-K (red), Ca- $L_{2,3}$  (blue) and Mn- $L_{2,3}$  (green) maps, respectively, c) the corresponding structural model of the orthorhombic perovskite-type phase, d) and e) the extracted elemental map of the Ca- $L_{2,3}$  and Mn- $L_{2,3}$  edges, respectively. The acquired EELS spectra were reconstructed applying the principal component analysis method after background subtraction using a power-law fit. Blue, green, and red circles correspond to the positions of Ca, Mn, and O atoms, respectively.



1 nm

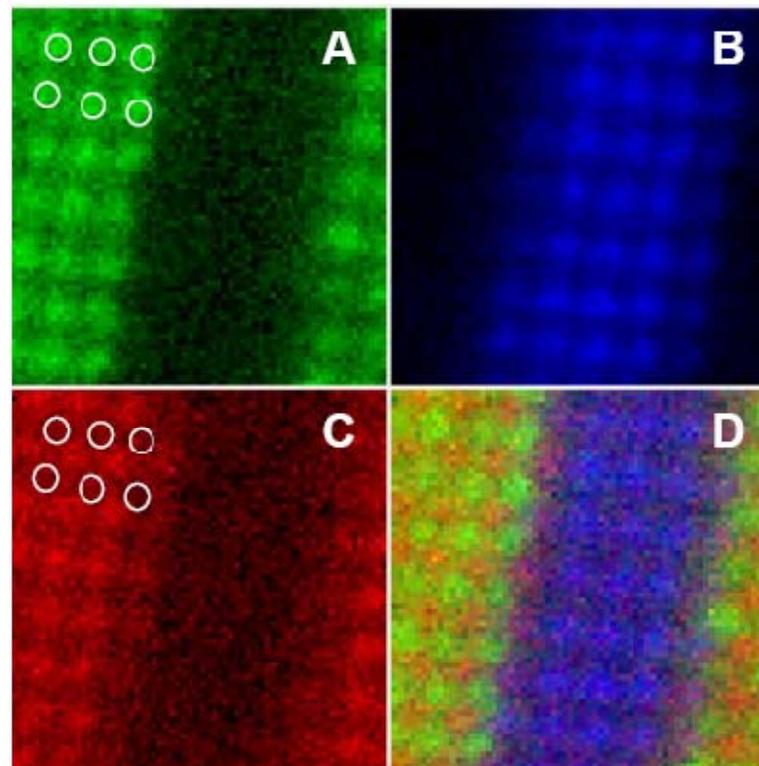


Spectroscopic imaging of LMO down the pseudocubic  $\langle 110 \rangle$  axis. The sketch shows the projected structure of LMO down this direction. In green, the O K edge image; in blue the simultaneously acquired Mn L<sub>2,3</sub> image and in red the La M<sub>4,5</sub> image. The RGB overlay of the three elemental maps is also shown.

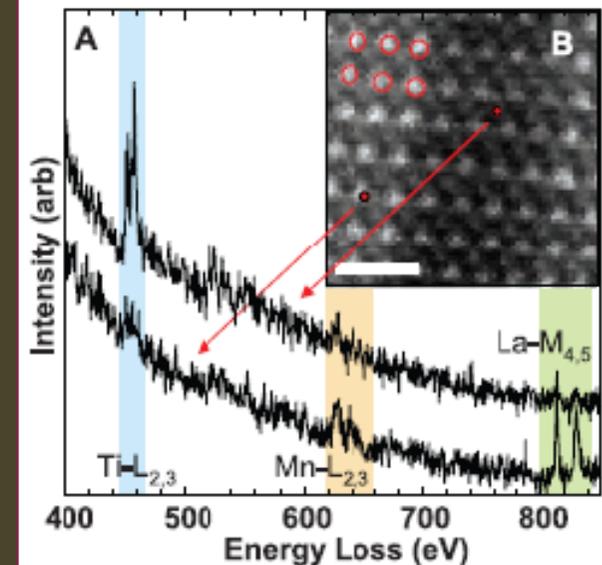
From M. Varela et al. to be published in MRS bulletin 01/2012

# Atomic-Scale Chemical Imaging of Composition and Bonding by Aberration-Corrected Microscopy

D. A. Muller,<sup>1,2\*</sup> L. Fitting Kourkoutis,<sup>1</sup> M. Murfitt,<sup>3</sup> J. H. Song,<sup>4,5</sup> H. Y. Hwang,<sup>5,6</sup>  
J. Silcox,<sup>1,2</sup> N. Dellby,<sup>3</sup> O. L. Krivanek<sup>3</sup>

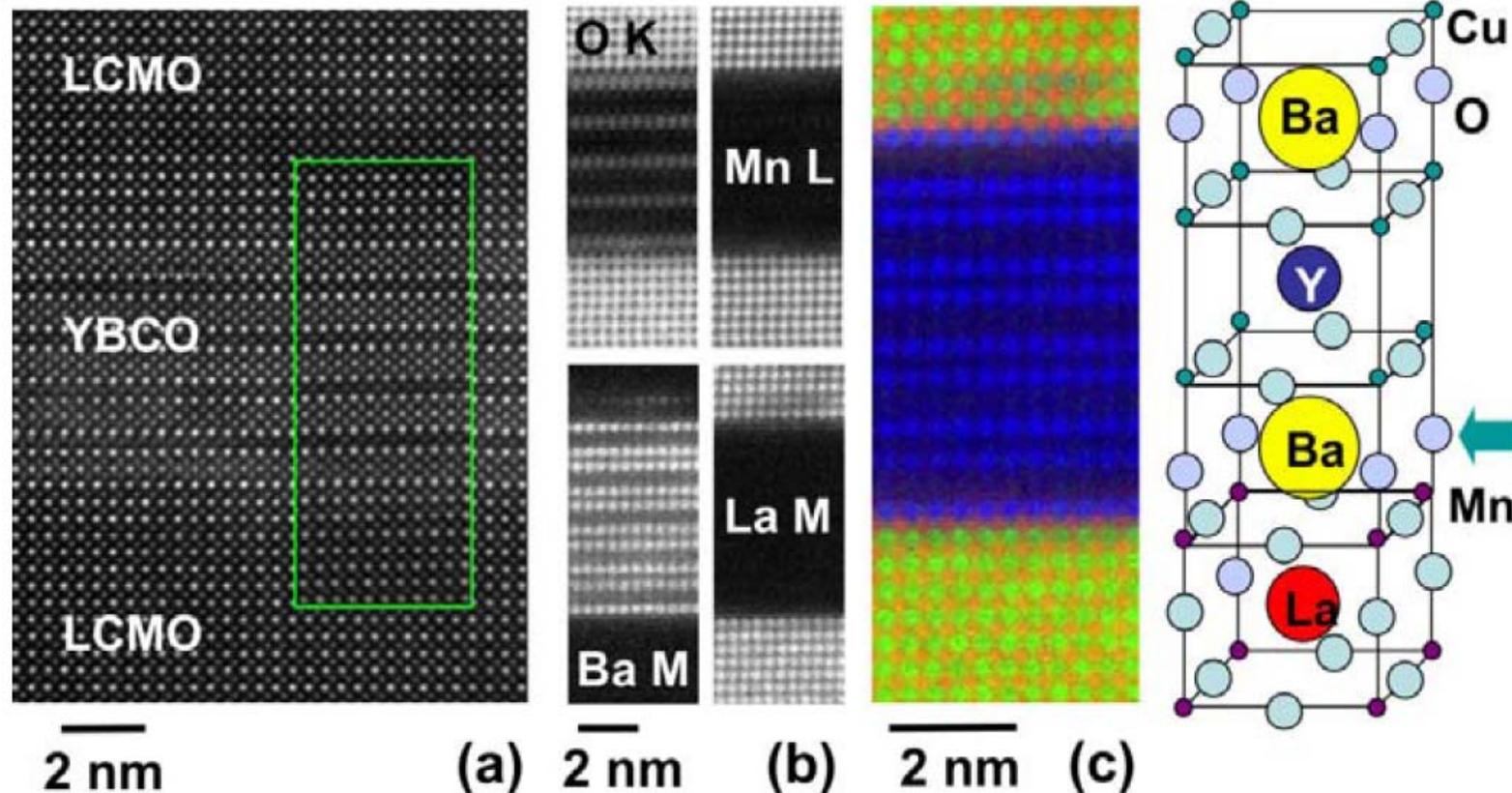


**Fig. 1.** Spectroscopic imaging of a  $\text{La}_{0.7}\text{Sr}_{0.3}\text{MnO}_3/\text{SrTiO}_3$  multilayer, showing the different chemical sublattices in a  $64 \times 64$  pixel spectrum image extracted from 650 eV-wide electron energy-loss spectra recorded at each pixel (A) La M edge; (B) Ti L edge; (C) Mn L edge; (D) red-green-blue false-color image obtained by combining the rescaled Mn, La, and Ti images. Each of the primary color maps is rescaled to include all data points within two standard deviations of the image mean. Note the lines of purple at the interface in (D), which indicate Mn-Ti intermixing on the B-site sublattice. The white circles indicate the position of the La columns, showing that the Mn lattice is offset. Live acquisition time for the  $64 \times 64$  spectrum image was  $\sim 30$  s; field of view, 3.1 nm.



**Fig. 2.** (A) Individual EELS spectra from the series shown in Fig. 1. (B) The simultaneously recorded annular dark-field (ADF) image. The large red circles show that the La signal from Fig. 1A is correctly peaked where the ADF scattering is strongest. The small red dots indicate the spatial locations from which the EELS spectra were selected. Scale bar, 1 nm.

D. Muller et al. Science 319 (2008) 1073

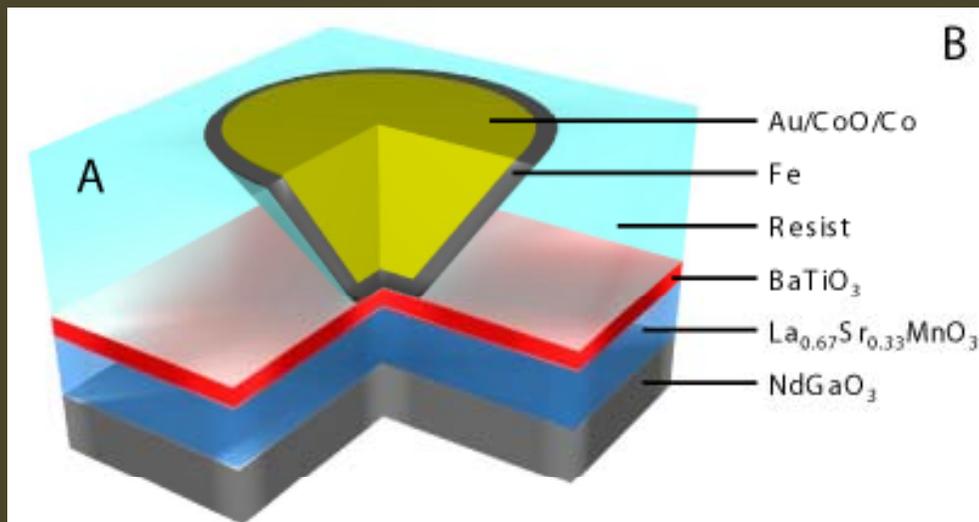


High resolution Z-contrast image of a LCMO/YBCO/LCMO heterostructure. The inset marks the region where an EELS spectrum image was acquired, along with the simultaneous ADF signal. (b) O K, Mn L<sub>2,3</sub>, Ba M<sub>4,5</sub> and La M<sub>4,5</sub> atomic resolution images. (c) RGB overlay of the Mn (red), La (green) and Ba (blue) images in (b). The sketch shows the interface structure.

From M. Varela et al. to be published in MRS bulletin 01/2012

# Ferroelectric control of spin polarization (Tunnel ElectroMagneto Resistance – TEMR)

→ tunnel junctions with ferromagnetic electrodes for large nonvolatile control of carrier spin polarization by switching ferroelectric polarization



- Fe electrode
- ultrathin BTO ferroelectric
- half-metallic LSMO as spin detector
- NGO: substrate

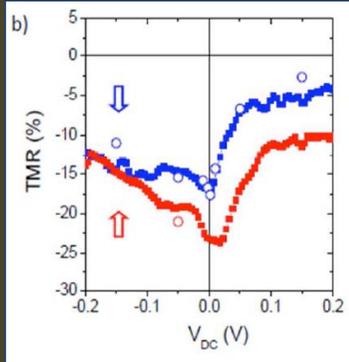
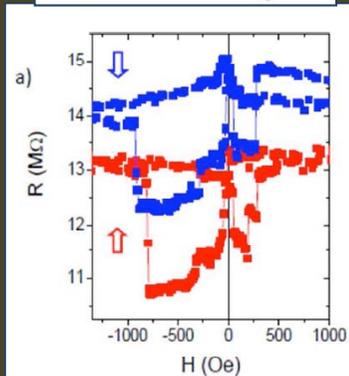
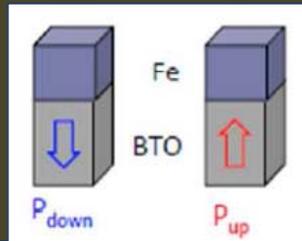
## Information provided from STEM/EELS analyses

- \* Structural quality of the film growth and the interfacial area
- \* Termination planes at the interfaces
- \* Oxidation states of the TM at the atomic scale

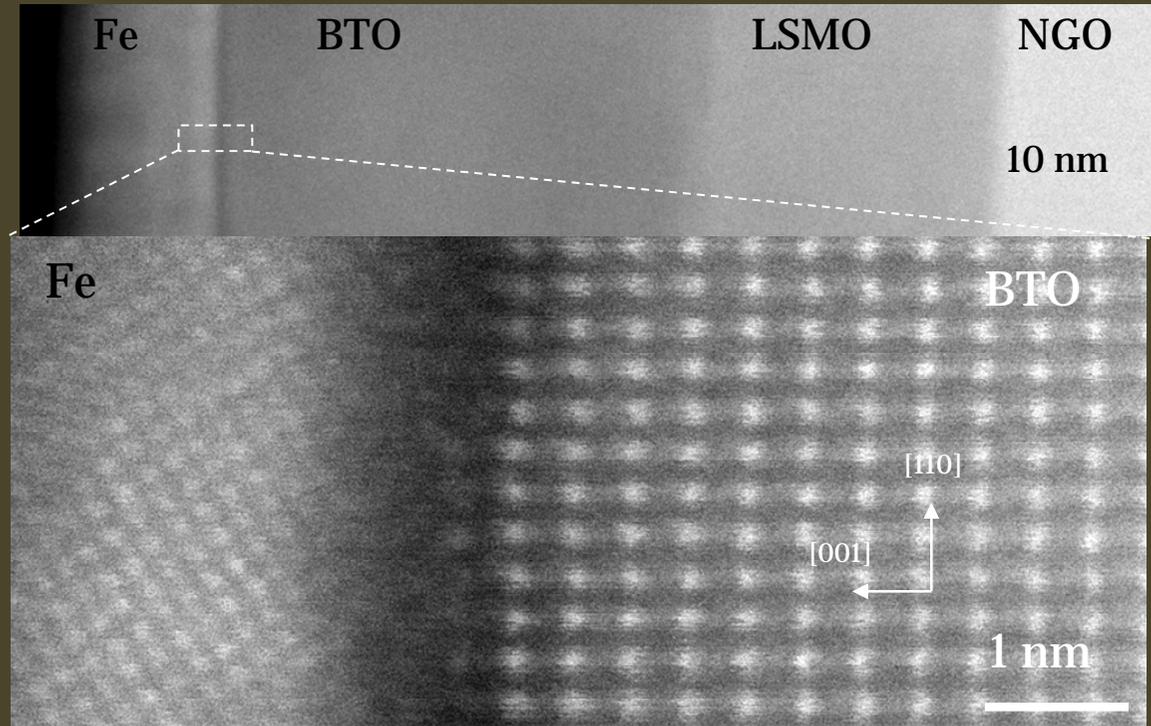
In order to understand the electromagnetic coupling at the FE/FM interface

# Ferroelectric control of spin polarization

V. Garcia et al (Thales/CNRS Palaiseau, LPS Orsay, U. Cambridge)



TMR (H) measured for reversed bias polarities on the ferroelectric junction

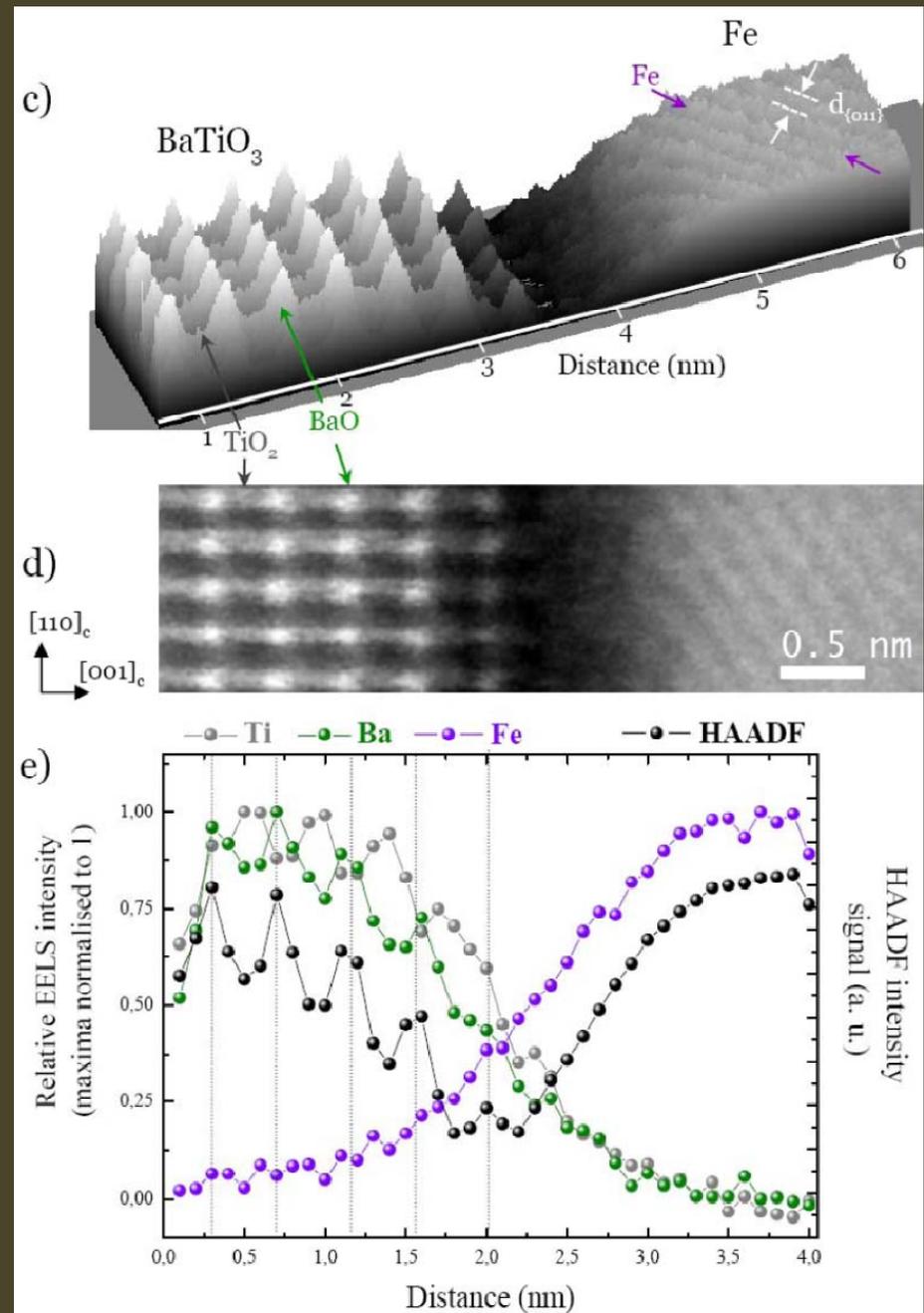
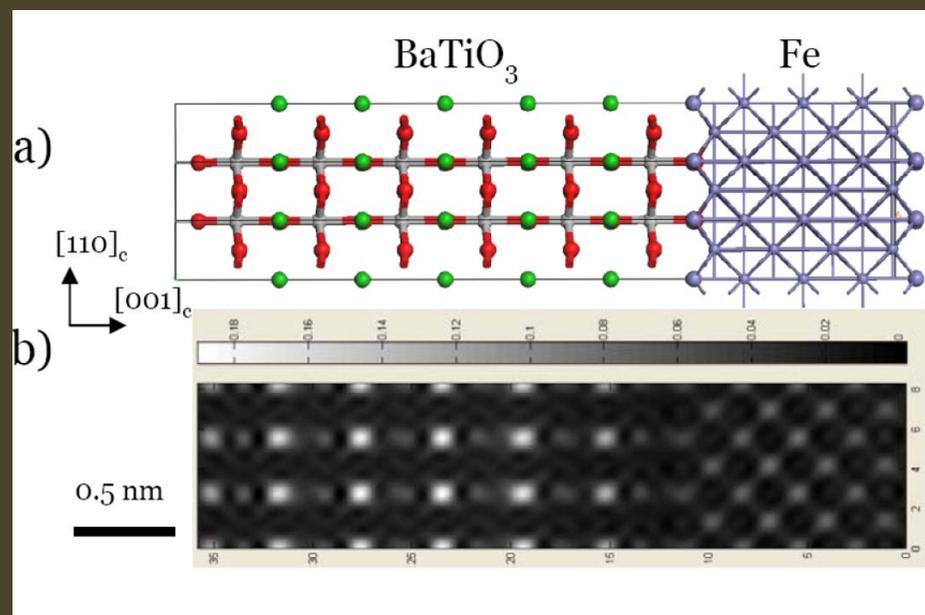


USTEM data courtesy A. Gloter & L. Bocher  
L. Bocher et al. submitted (2011)

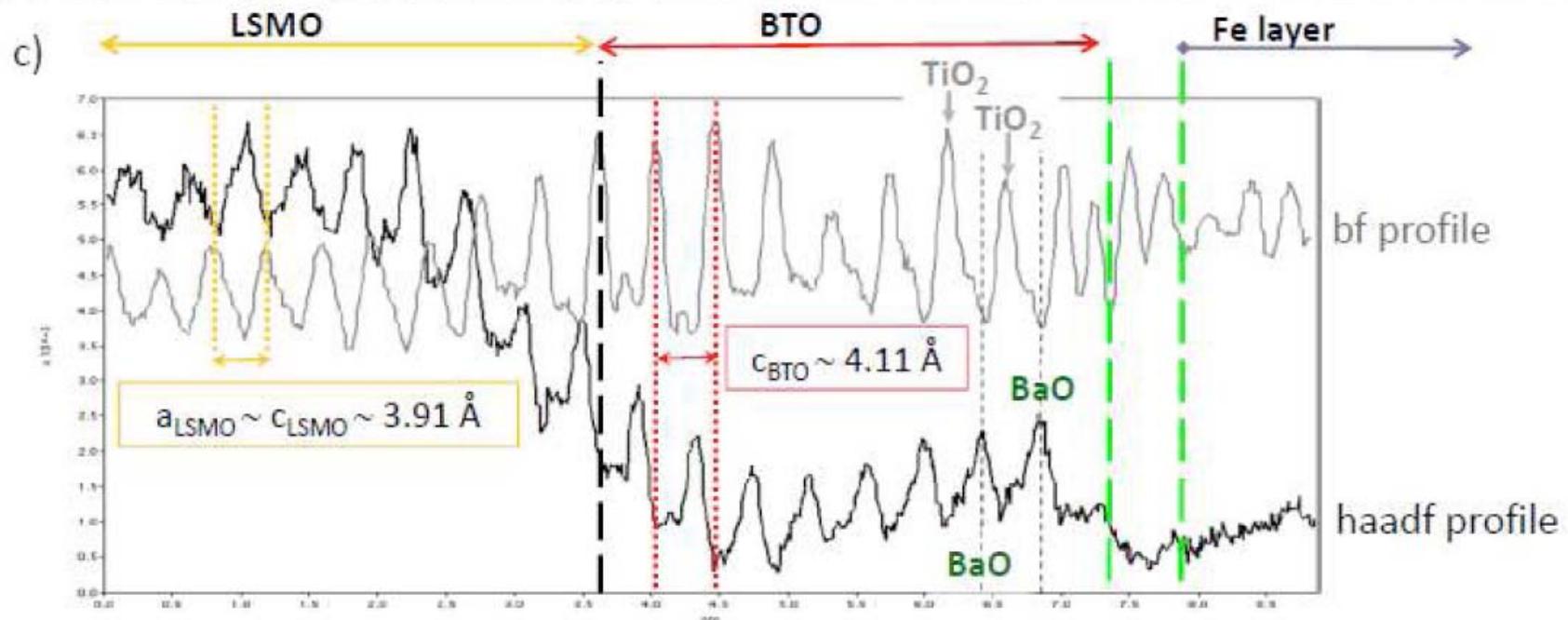
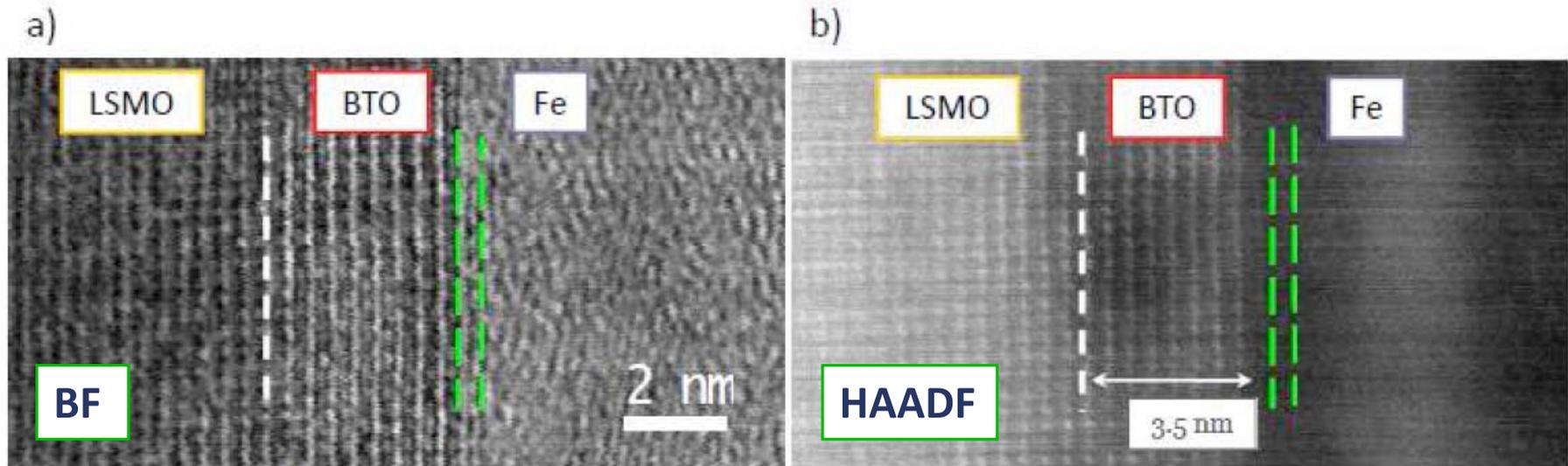
## BaTiO<sub>3</sub>/Fe interface

- i) one possible structure model
- ii) image simulation
- iii) and iv) HAADF experimental images
- iv) elemental profiles

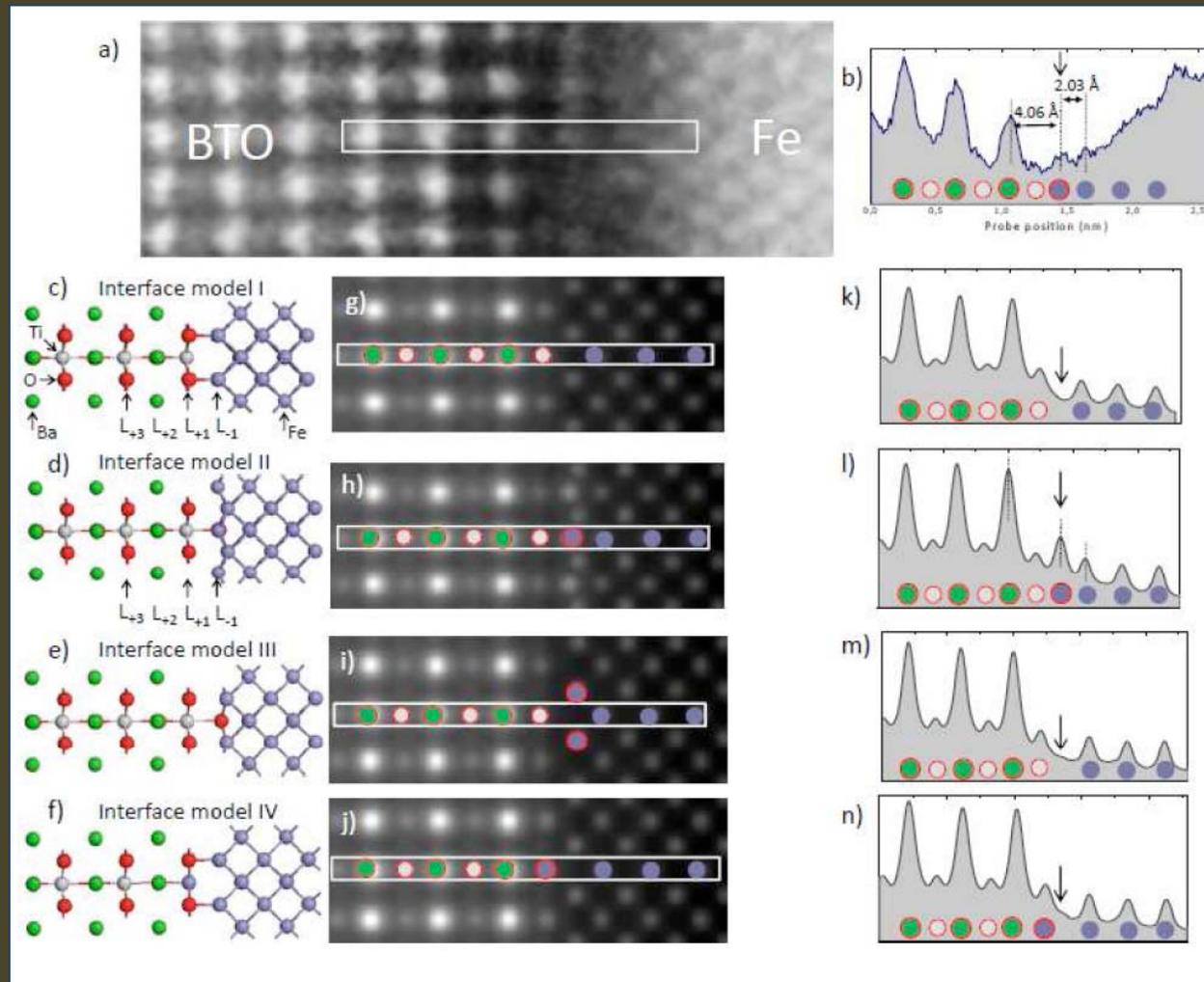
Courtesy L. Bocher & A. Gloter  
JOM 62 (12/2010) 53-57



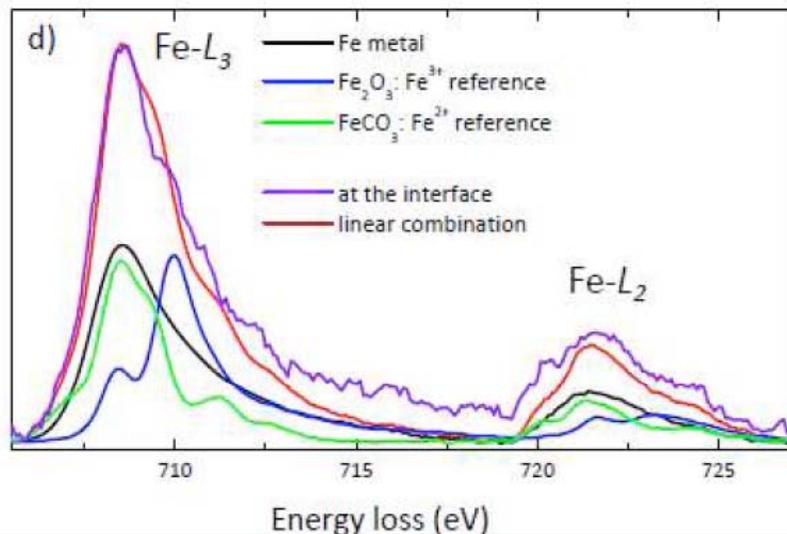
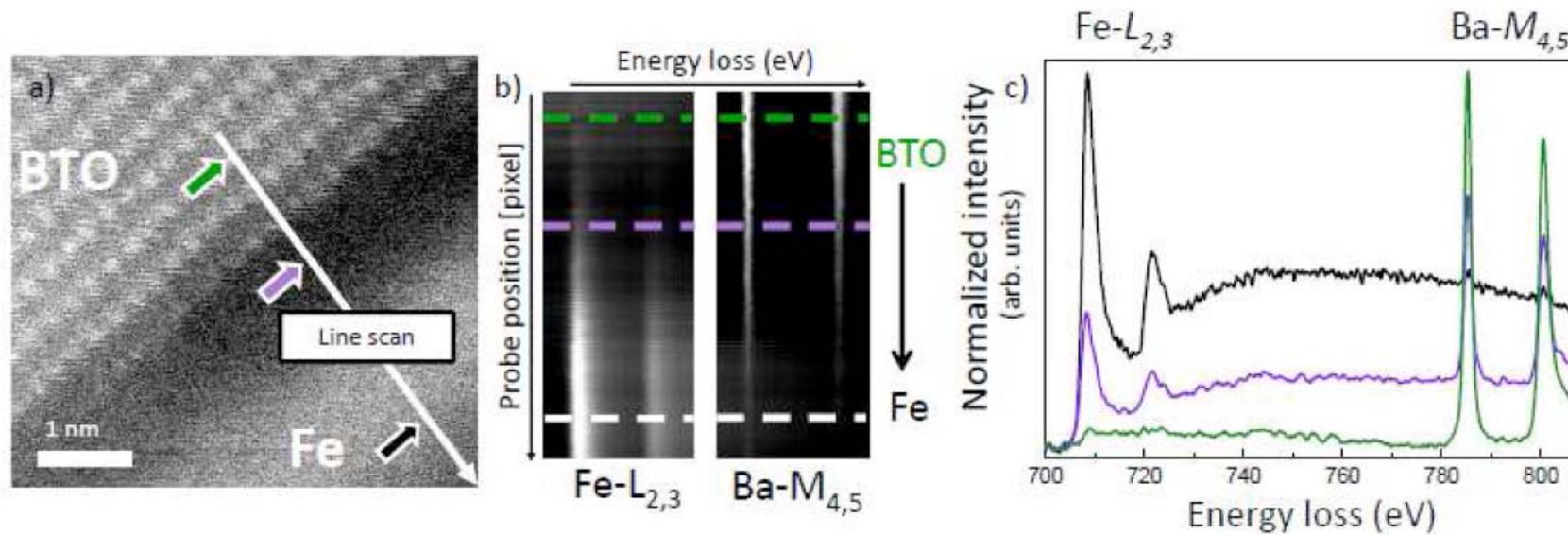
# STEM imaging the interface BTO-Fe



# Atomic structure at the interface : comparison experiment, models and simulations



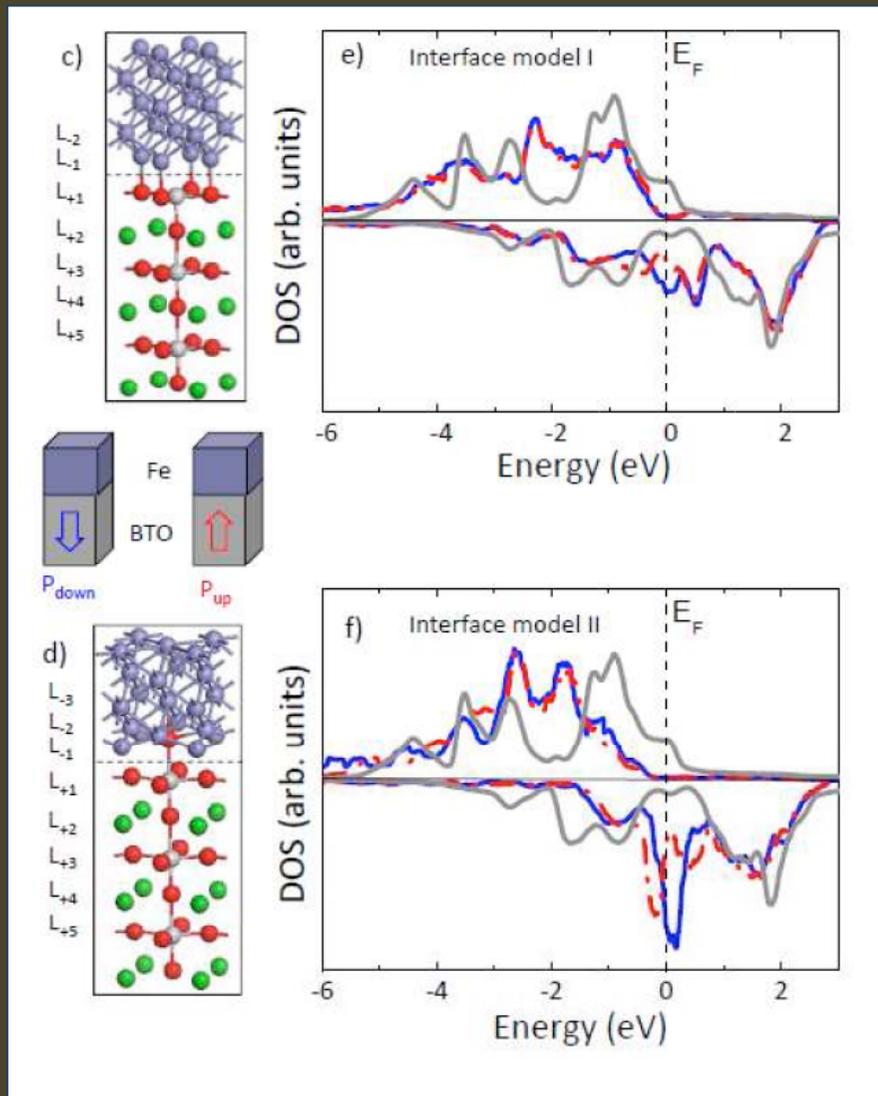
# Elemental composition and Fe EELS $L_{2,3}$ fine structures across the interface



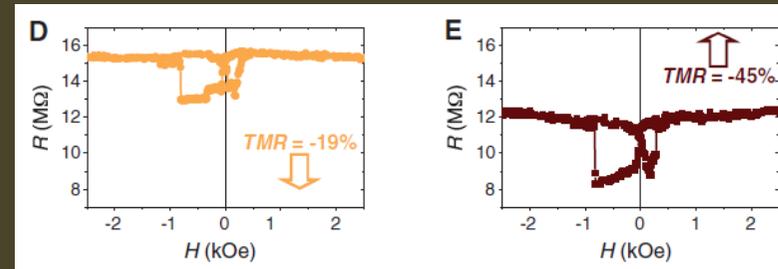
➔ Presence of oxidized Fe (in the Fe<sup>2+</sup> as well as in the Fe<sup>3+</sup> state) over one atomic layer at the interface

L. Bocher et al. submitted (2011)

# Modelling the interface and electronic structure calculations



DFT calculations  
of the spin polarisation



Interface model I

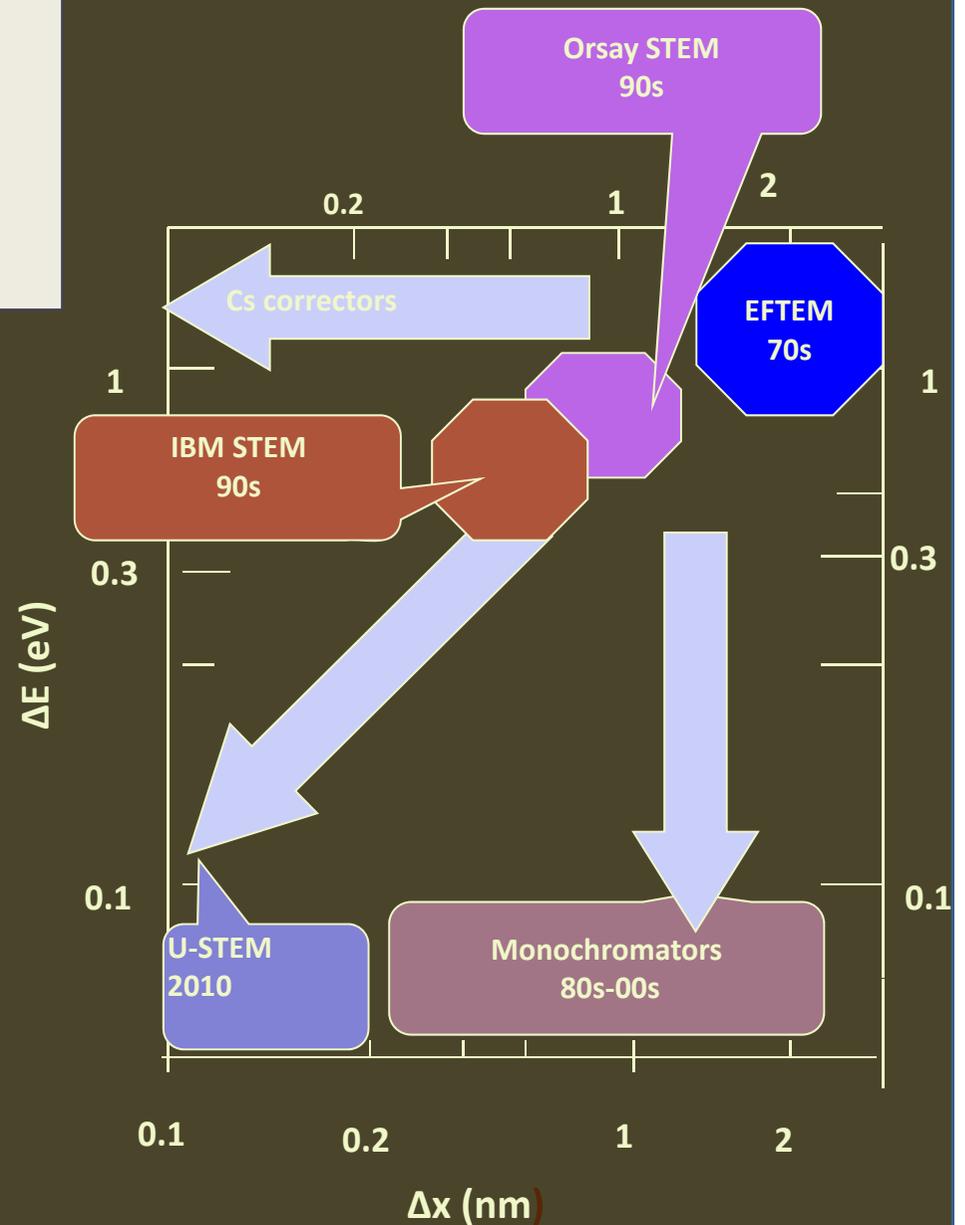
Interface model II

	Fe [P <sub>up</sub> ]	2.07		Fe [P <sub>up</sub> ]	2.09
Fe (L <sub>3</sub> )	Fe [P <sub>down</sub> ]	2.06	Fe (L <sub>3</sub> )	Fe [P <sub>down</sub> ]	2.05
	$\Delta \mu_{\text{Fe}}$	> 0.01		$\Delta \mu_{\text{Fe}}$	0.04
	Fe [P <sub>up</sub> ]	2.04		Fe [P <sub>up</sub> ]	2.35
Fe (L <sub>2</sub> )	Fe [P <sub>down</sub> ]	2.08	Fe (L <sub>2</sub> )	Fe [P <sub>down</sub> ]	2.34
	D $\mu_{\text{Fe}}$	-0.04		$\Delta \mu_{\text{Fe}}$	0.01
	Fe [P <sub>up</sub> ]	2.12		Fe [P <sub>up</sub> ]	2.85
Fe (L <sub>1</sub> )	Fe [P <sub>down</sub> ]	2.31	Fe (L <sub>1</sub> )	Fe [P <sub>down</sub> ]	2.76
	$\Delta \mu_{\text{Fe}}$	-0.19		$\Delta \mu_{\text{Fe}}$	0.09

# Trends of the accessible performance in terms of spatial and spectral resolution (updated in 2010)

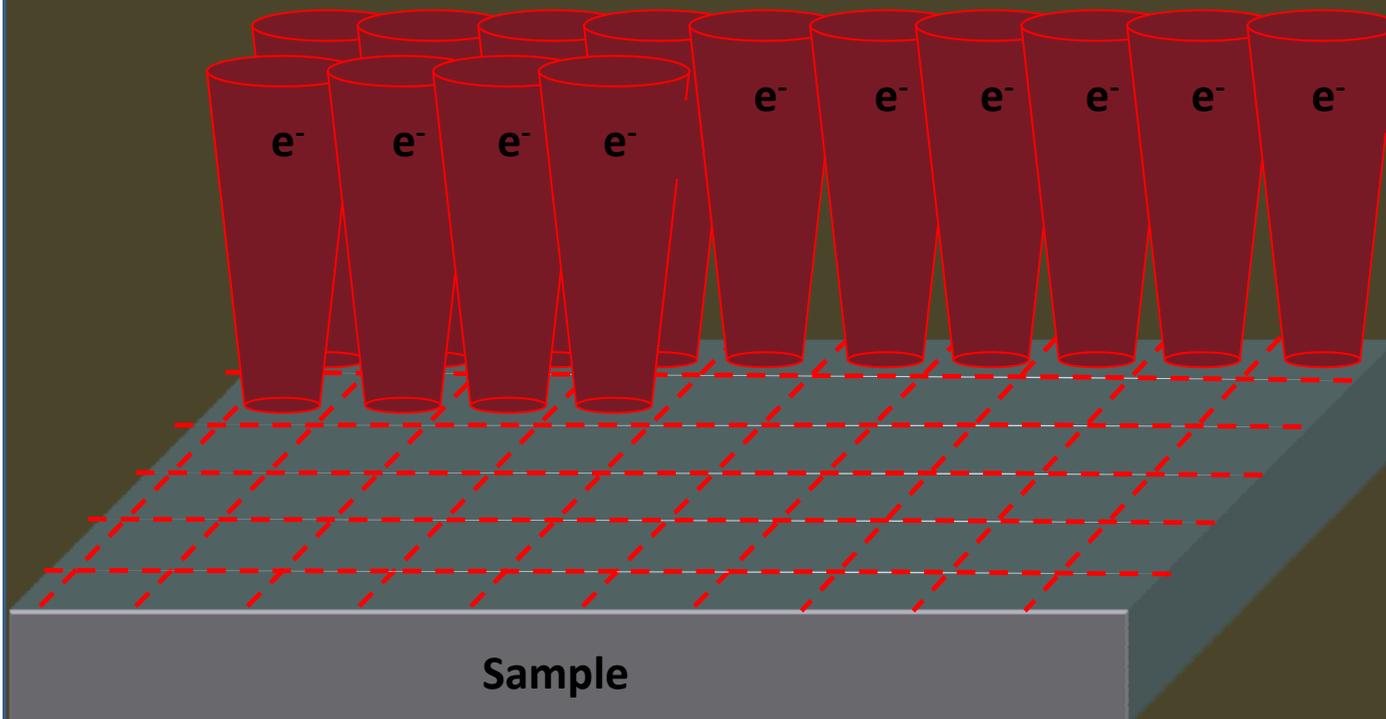
Must be accompanied with a parallel development in data processing and modelization tools (propagation of a sub-angstrom electron probe across a thin specimen, physics of the inelastic scattering, calculation of electron density of states...)

Where are we now ?



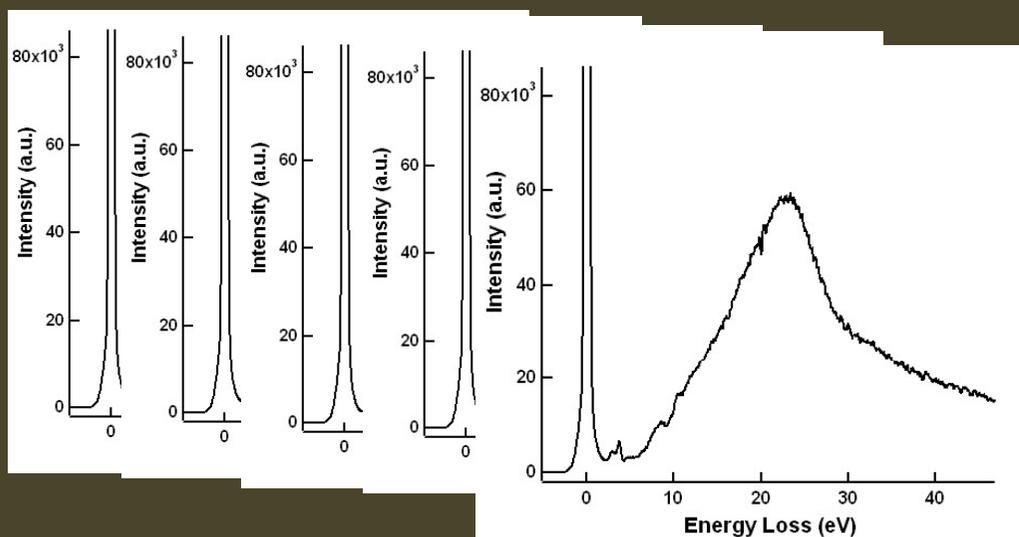
## **Mapping plasmons and EM fields**

## 4D (x,y,E,t) Spectrum-imaging mode



Improved  
energy  
resolution  
(0.2 eV)

at each pixel

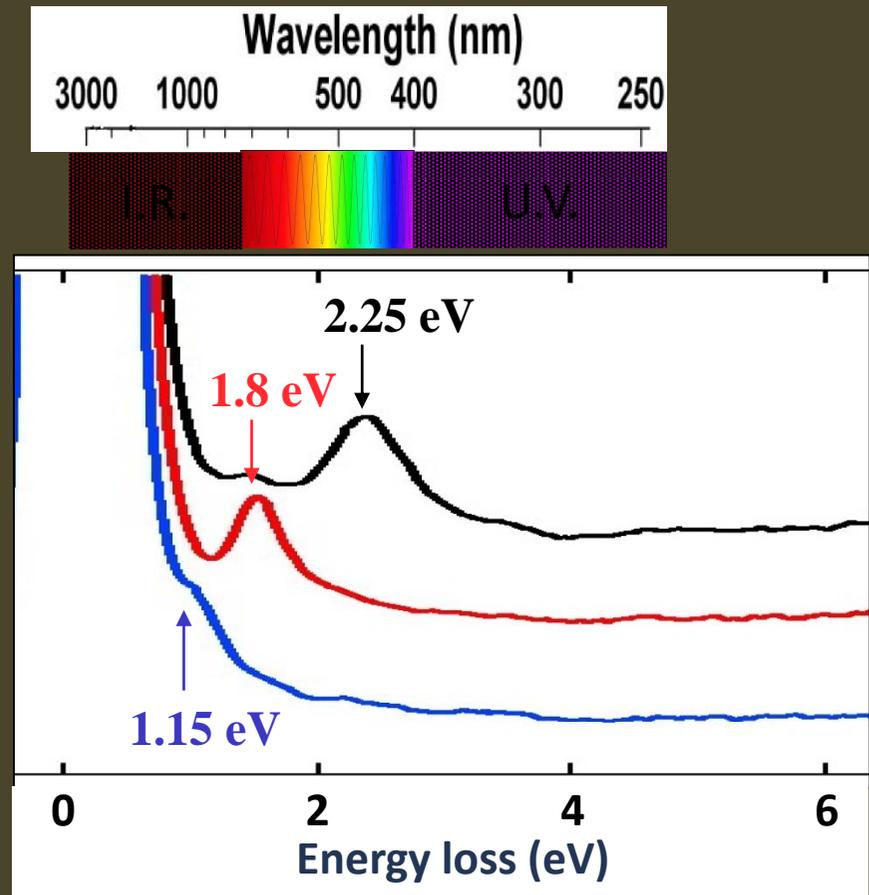
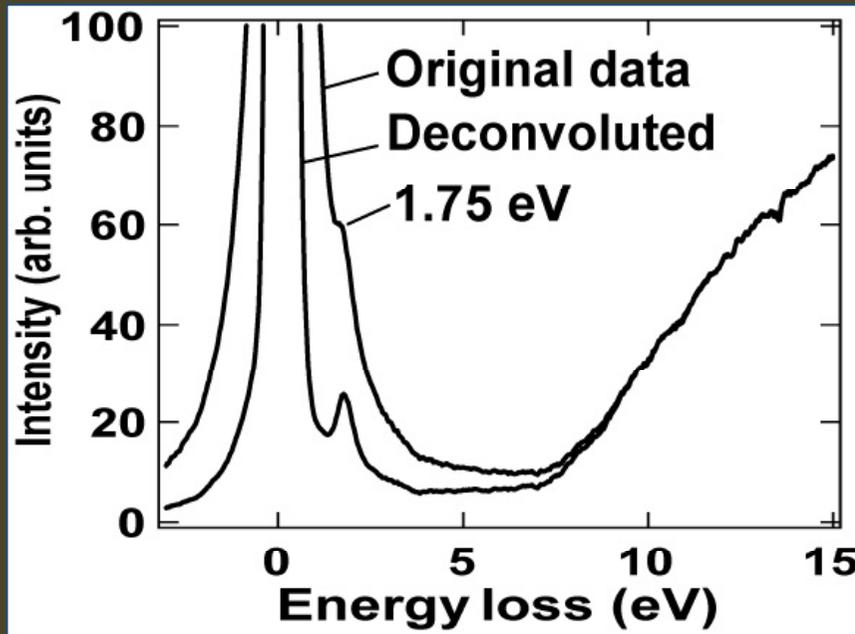


- 50 spectra/pixel
- 3 ms/spectrum
- deconvolution

+ HAADF signal

# New possibilities for studying the low energy-loss domain

Deconvolution techniques open the way to investigating nanophotonics with electrons



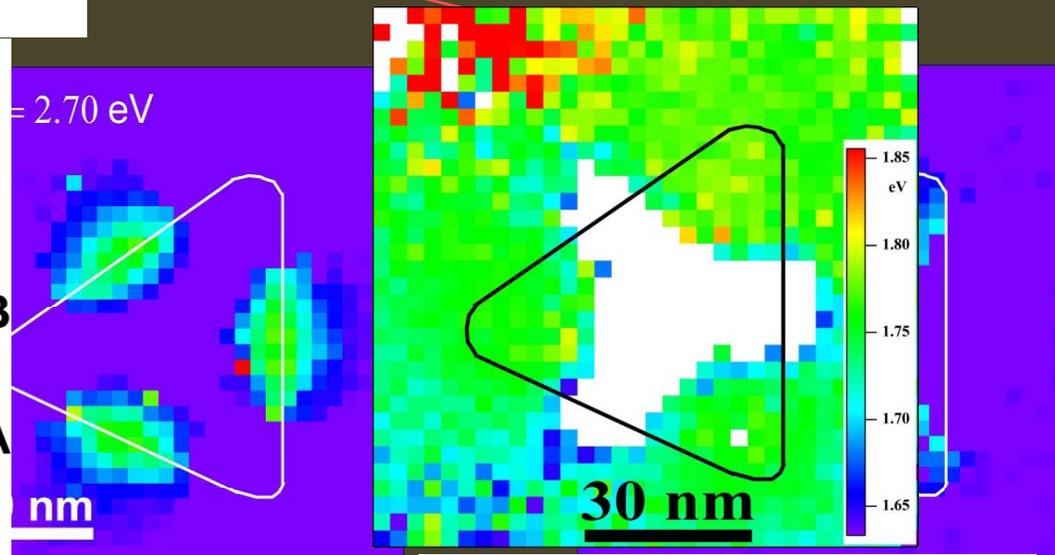
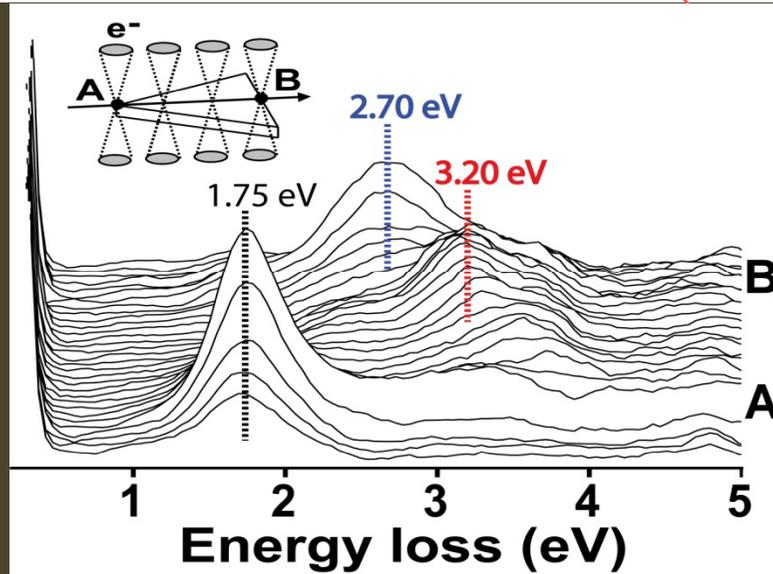
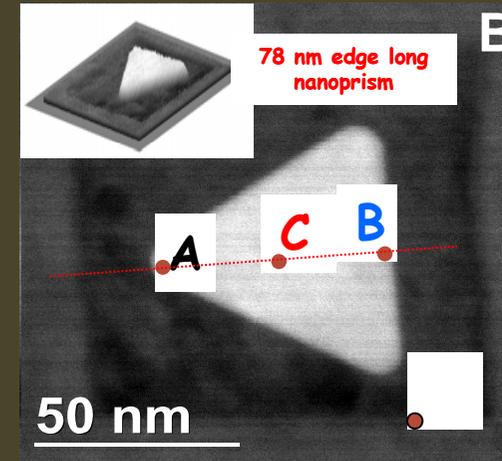
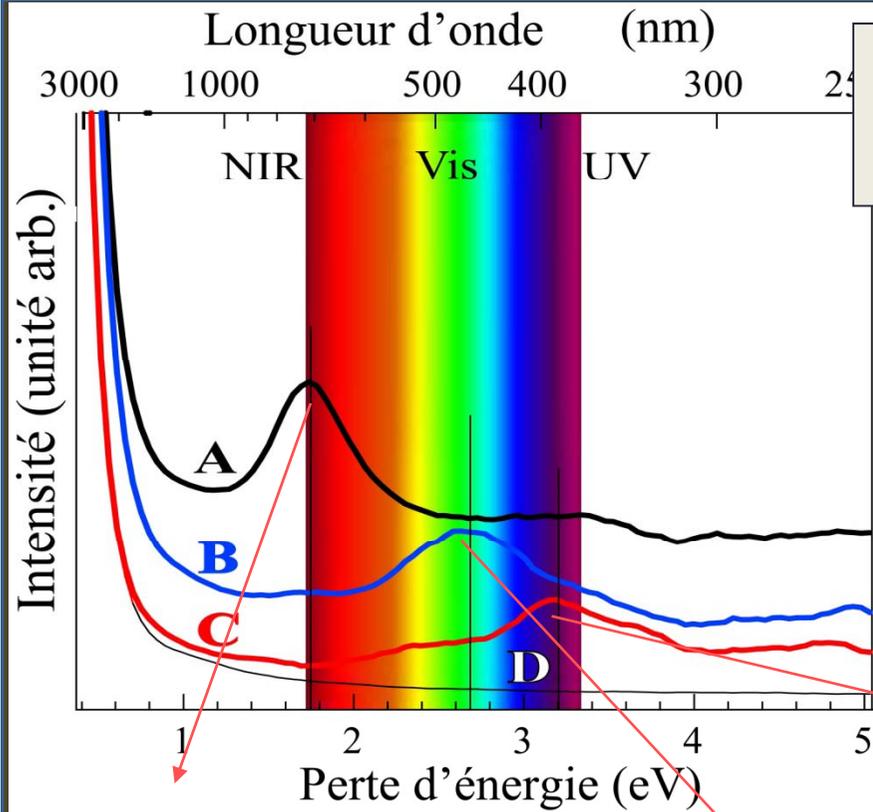
Increase in  $\Delta E$   
(from 0.35 eV to 0.25 eV)

Cut-off of zero loss signal  
at 0.9 eV (IR)

Higher  
signal-to-background ratio

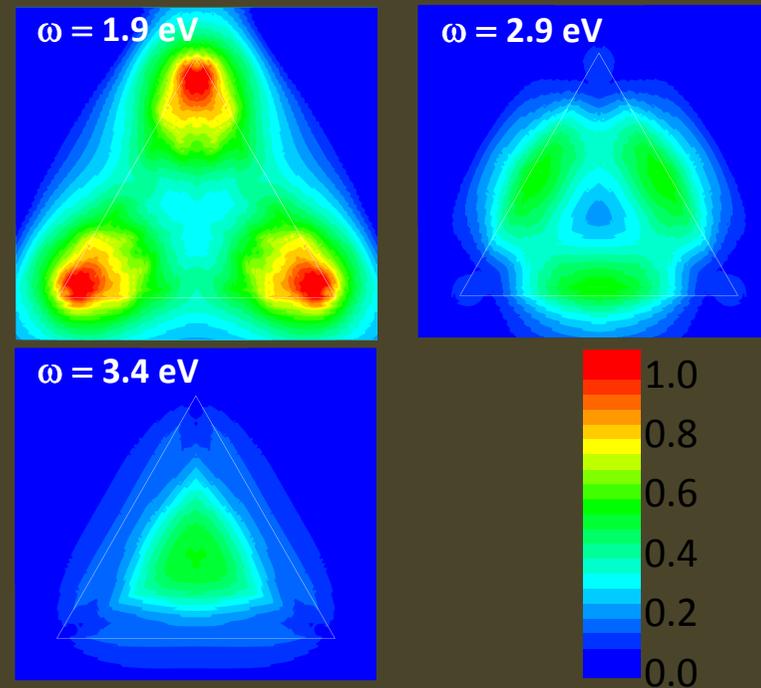
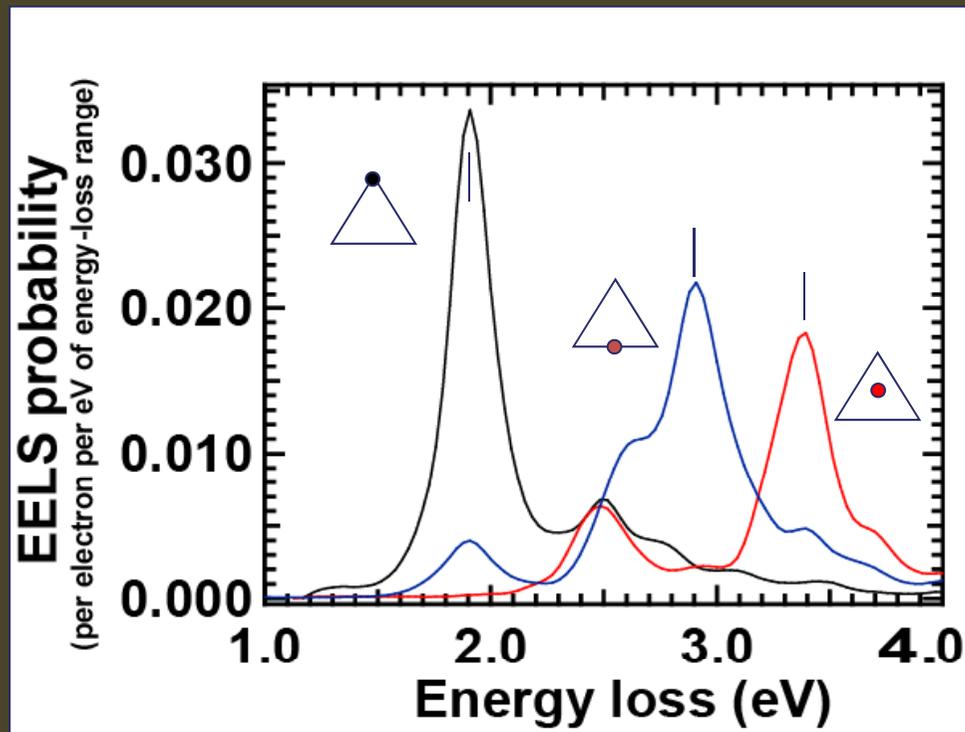
*New technical possibilities (A. Gloter, A Douiri, M. Tencé)*

# Mapping surface plasmon resonances of triangular silver nanoprisms

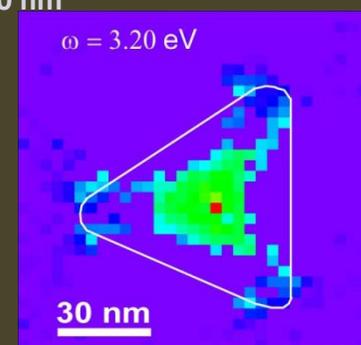
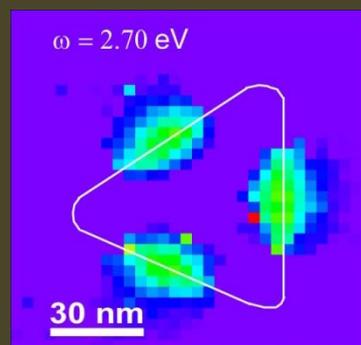
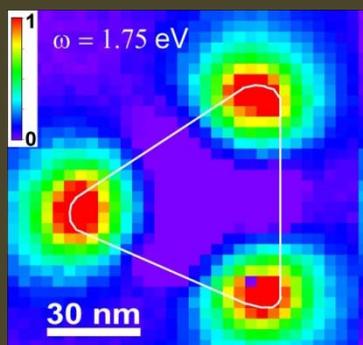


# EELS simulations of triangular Ag nanoprisms

(courtesy J. Garcia de Abajo, Madrid)

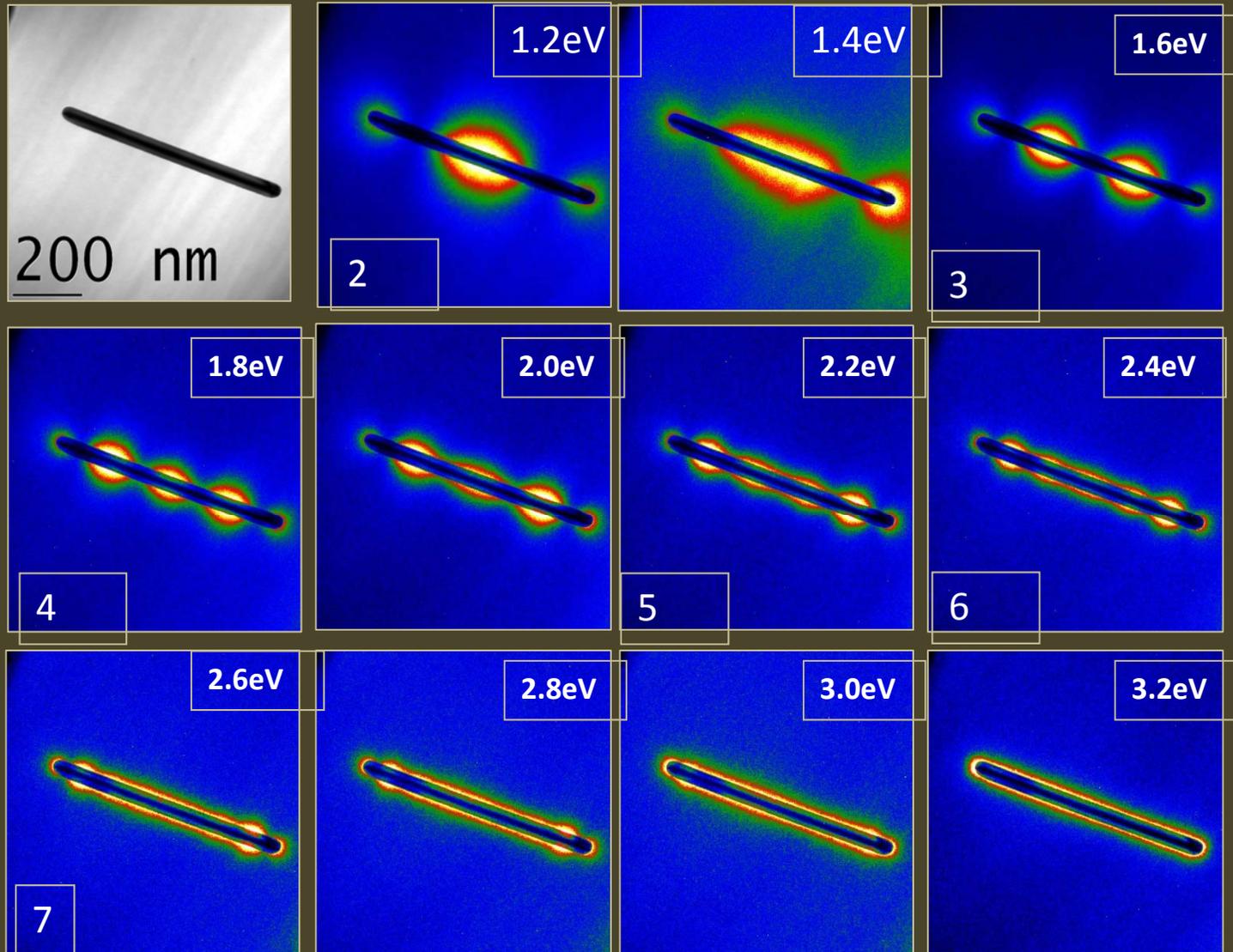


- 100 Kv electrons
- 78 nm long and 10 nm thick Ag prism



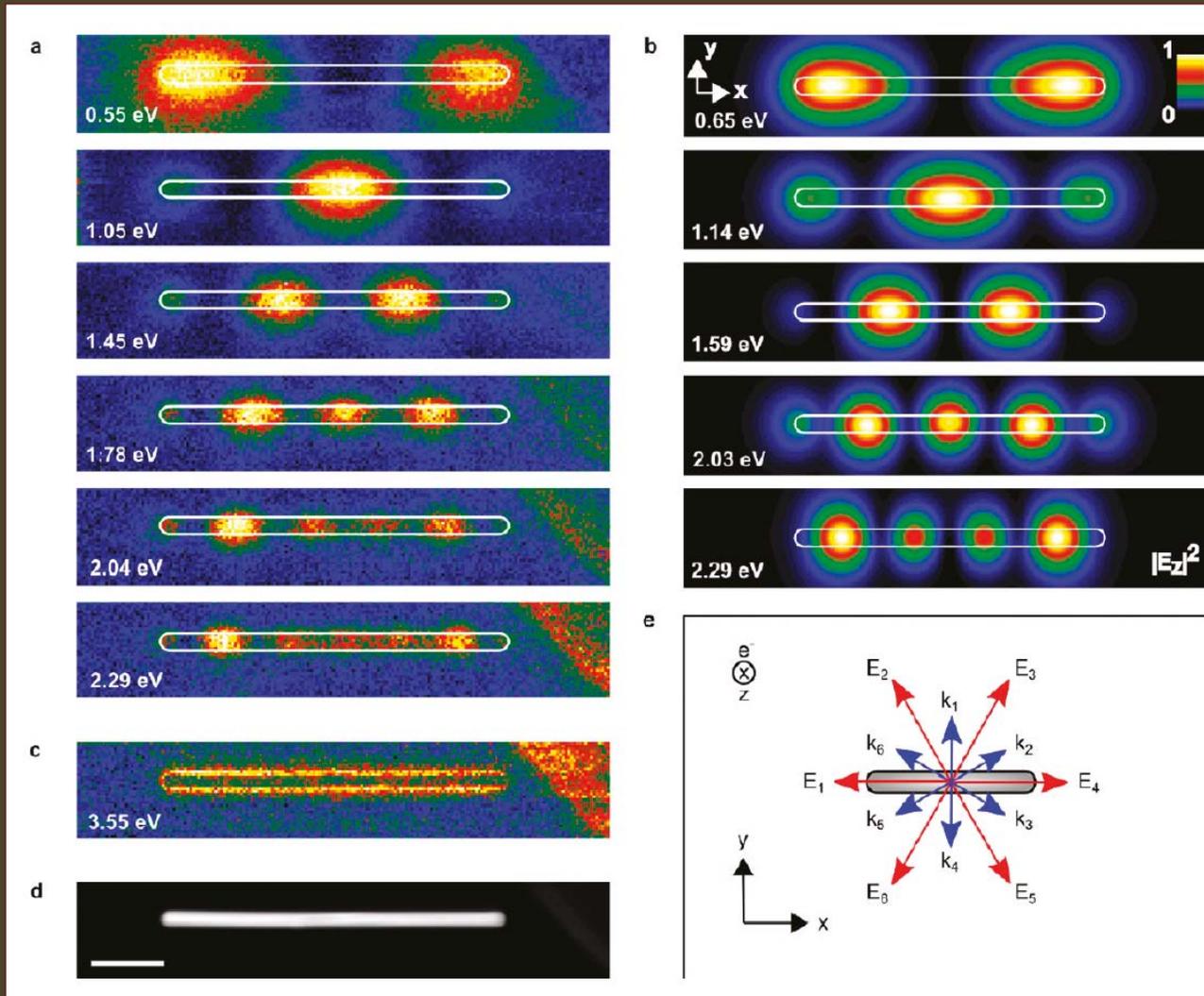
# Modes in an Ag nanoantenna (aspect ratio $L/r$ increases)

(coll. Cambridge-Stuttgart, courtesy P. Midgley)



EFTEM series on  
SESAM machine  
660 nm Ag nanorod  
0.2eV slit width

# Silver nanoantennas EELS (2)



Experiments versus simulations  
(DDA of  $|E_z|^2$  at 60 nm above antenna)

Nano Lett 11, 1499 (2011)

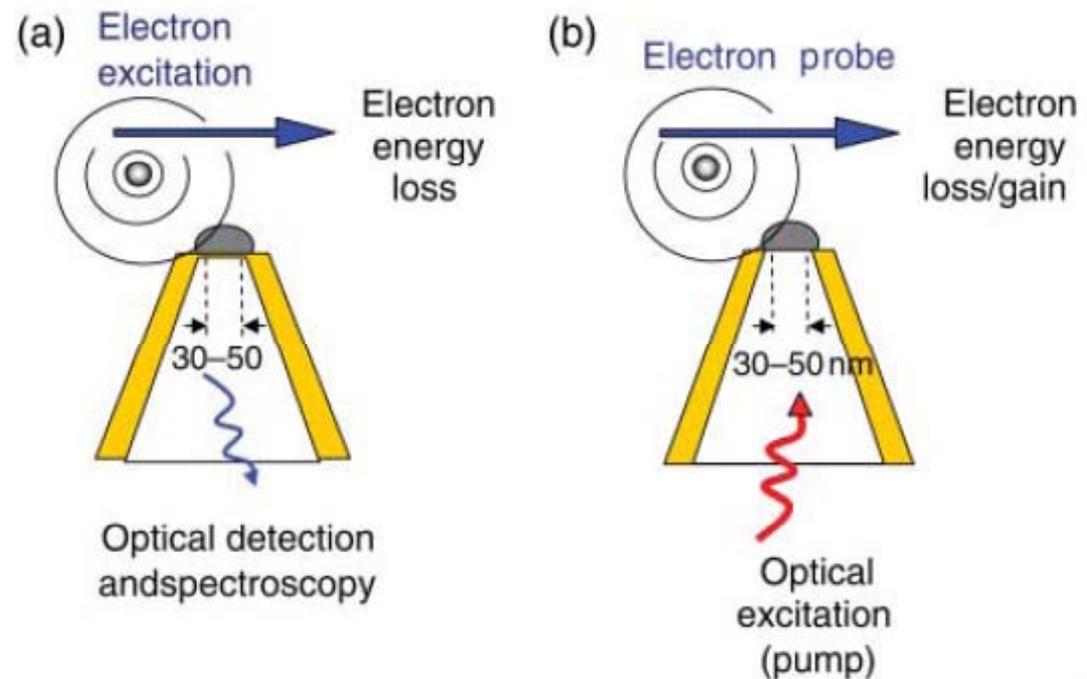
**When electrons and photons  
team up**

**« Multi-signal microscopy »**

« When electrons  
and photons  
team up »

by F.J. Garcia de Abajo  
(Nature 462 (2009) 861)

8 JOURNAL OF ELECTRON MICROSCOPY, 2011

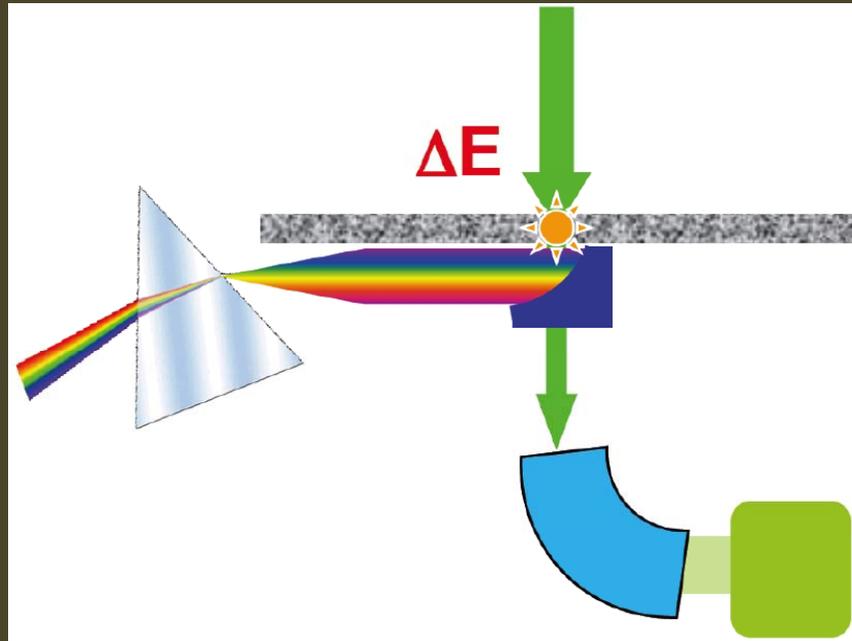


**Fig. 7.** Schematic description of novel multi-signal microscopies involving dual beams (photons and electrons) either as probing particles or as generated signals: one recognizes in (a) the conventional EELS (electron/electron) spectroscopy and the more original (electron /photon – either X or visible) mapping modes, and in (b) the much more innovative (photon/electron) mode corresponding to electron energy gain or electron energy loss of excited states, see text for further description (image courtesy of M. Kociak).

# Light detection (inserting a parabolic mirror within the VG pole piece)

home-made cold stage + light detector (L. Zagonel+ S. Mazzucco + M. Kociak)

Monochromatic electron beam



Electron Induced Radiation Emission (Cathodoluminescence)

Electron Energy-Loss Spectrum

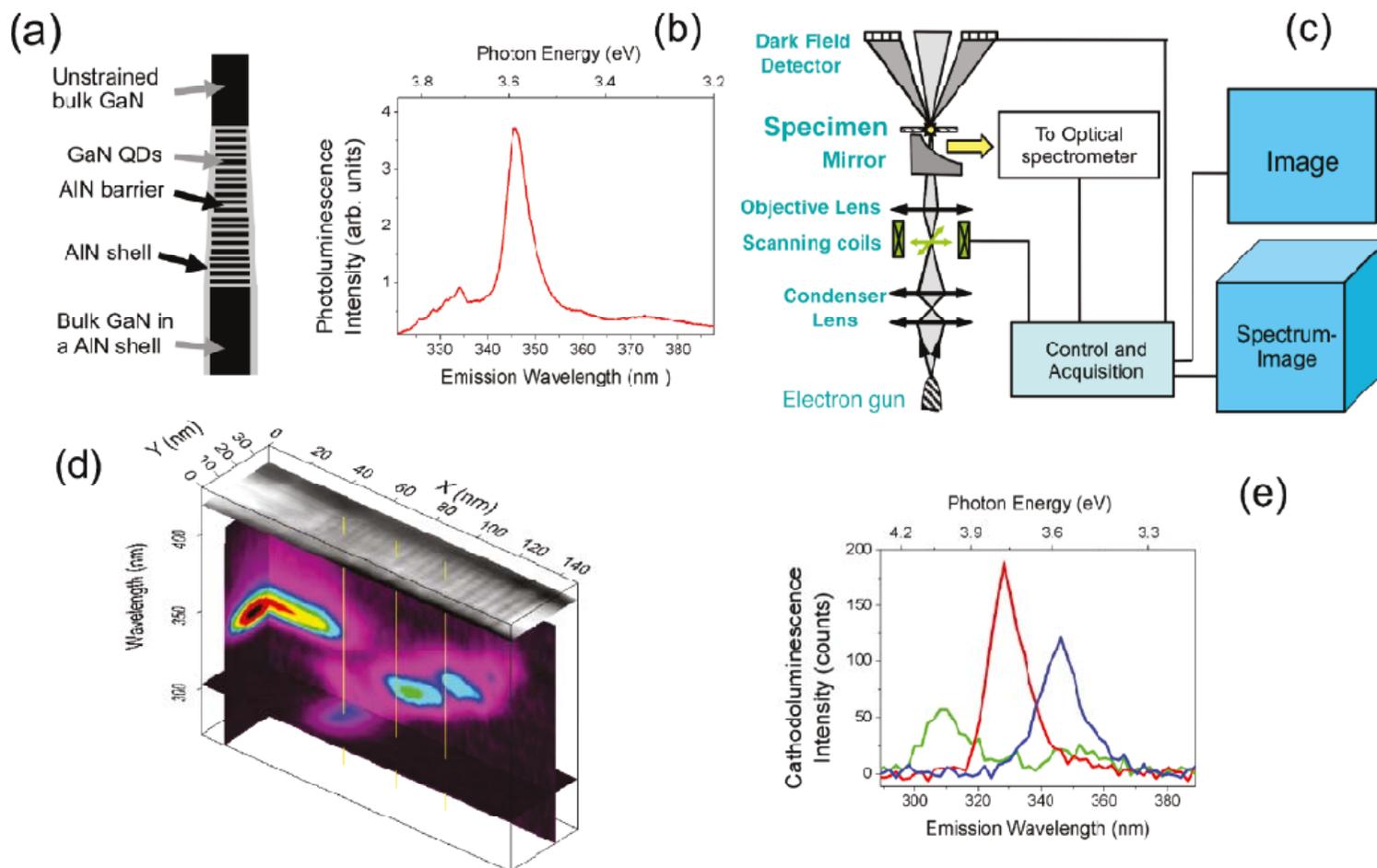
Emission by CL

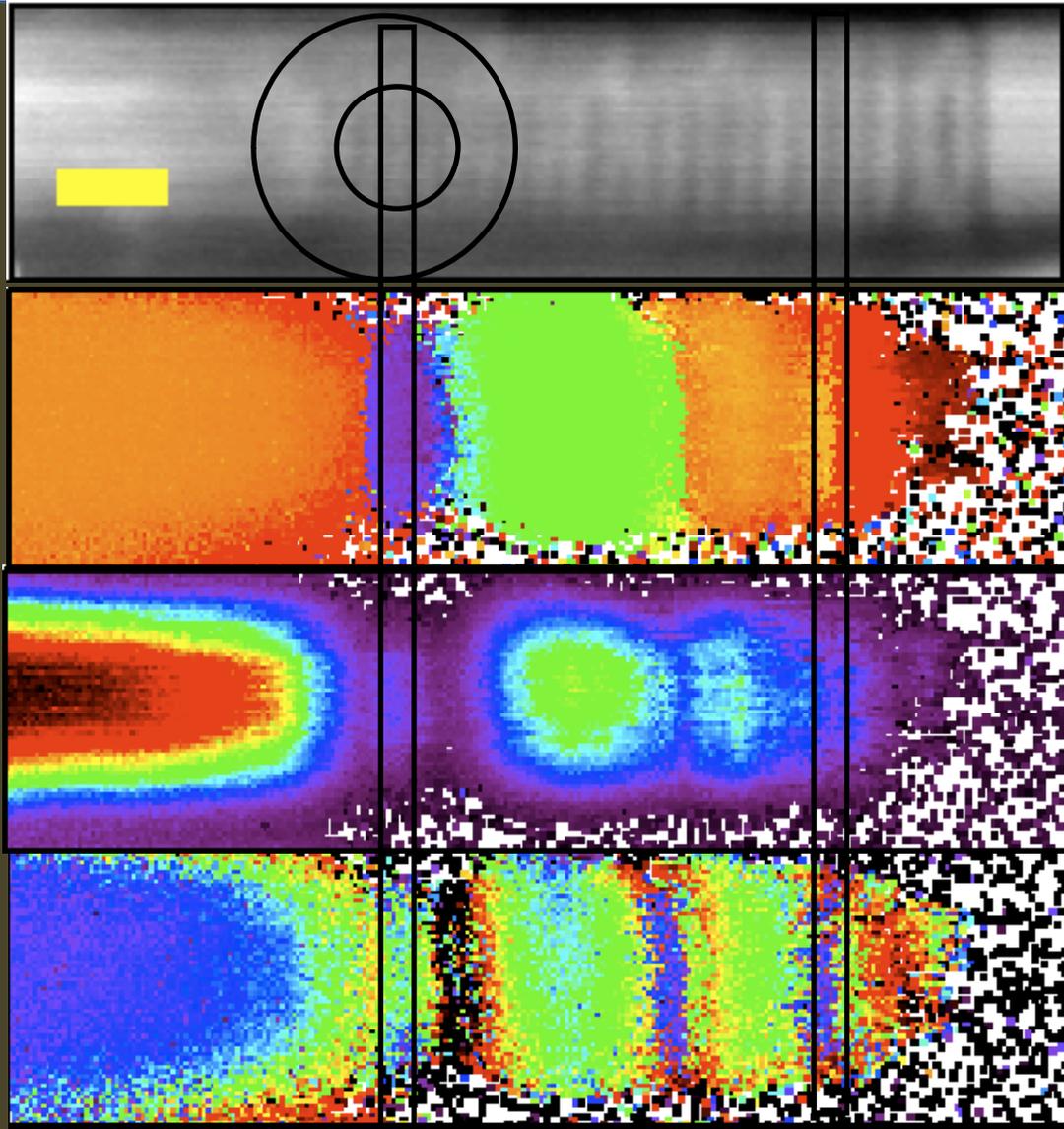
Absorption by EELS

2 patents (licensing opportunities)

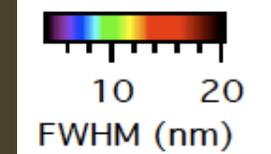
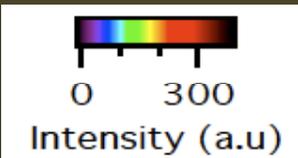
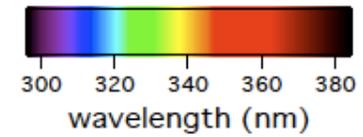
## Nanometer Scale Spectral Imaging of Quantum Emitters in Nanowires and Its Correlation to Their Atomically Resolved Structure

Luiz Fernando Zagonel,<sup>†</sup> Stefano Mazzucco,<sup>†</sup> Marcel Tencé,<sup>†</sup> Katia March,<sup>†</sup> Romain Bernard,<sup>†</sup> Benoit Laslier,<sup>†</sup> Gwénoél Jacopin,<sup>‡</sup> Maria Tchernycheva,<sup>‡</sup> Lorenzo Rigutti,<sup>‡</sup> Francois H. Julien,<sup>‡</sup> Rudeesun Songmuang,<sup>§</sup> and Mathieu Kociak<sup>\*,†</sup>





## 2D photon emission spectral-imaging

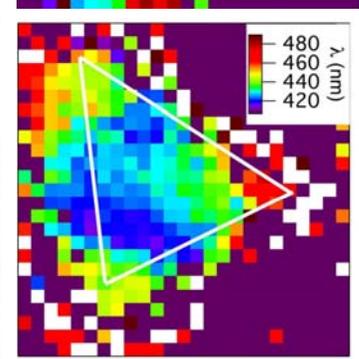
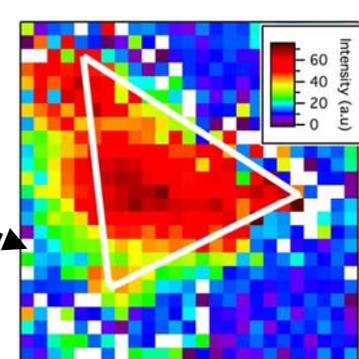
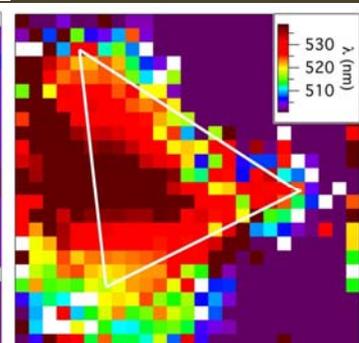
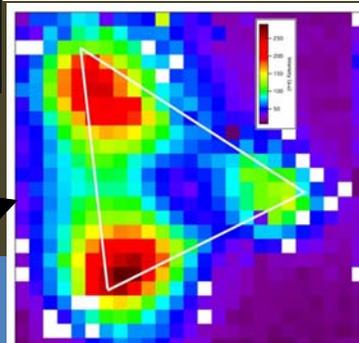
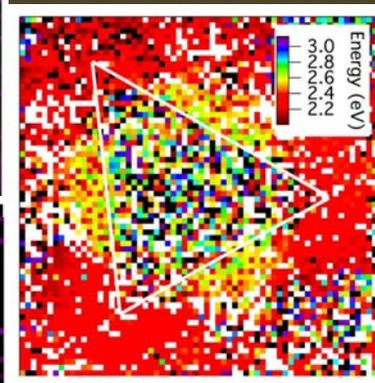
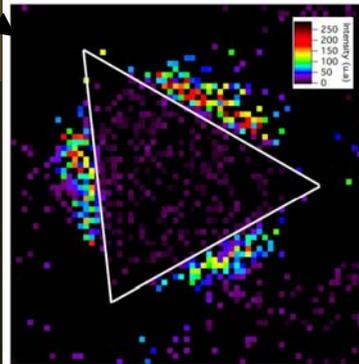
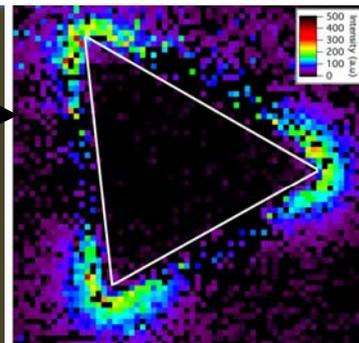
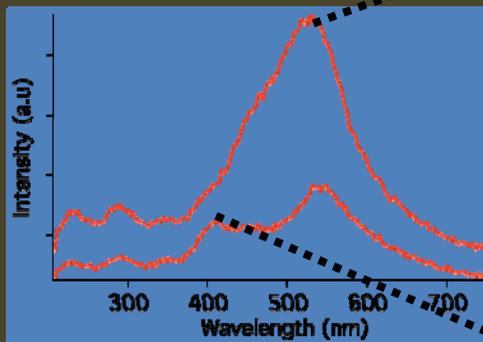
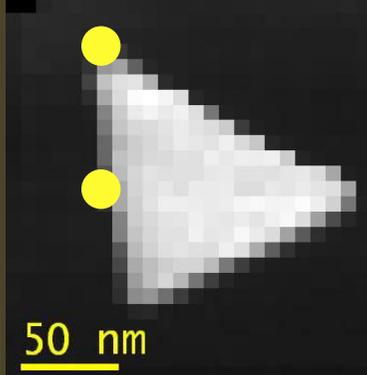
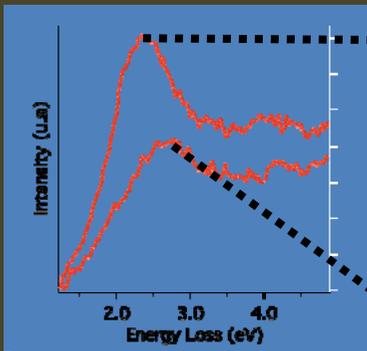
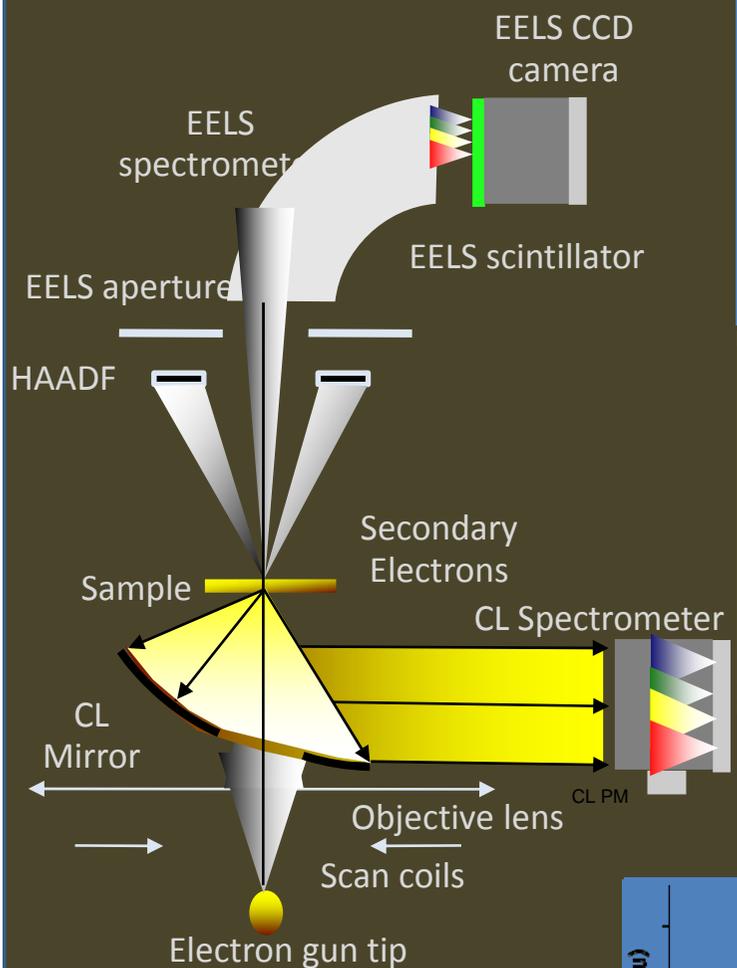


VG HB501

- ▶ Spatial sampling: 0.7 nm
- ▶ Spectral sampling: 2 nm (ca 8 meV)
- ▶ Individual QD optical properties revealed!

L. Zagonel, M. Kociak et al., NanoLetters 2011

# Spectral Imaging with electrons



M. Kociak et al., patents pending  
 L. Zagonel, A. Losquin et al., unpublished,

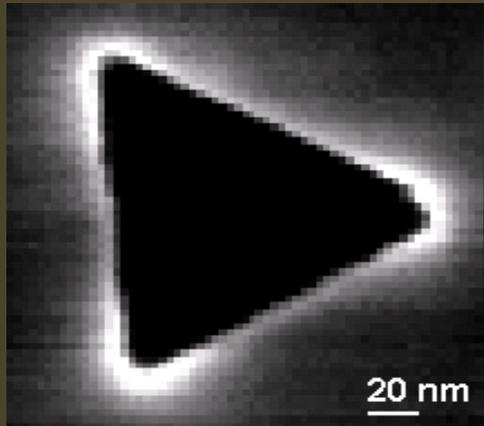
- ▶ Absorption and emission on the same object
- ▶ @ nm resolutions..

# Absorption and Emission

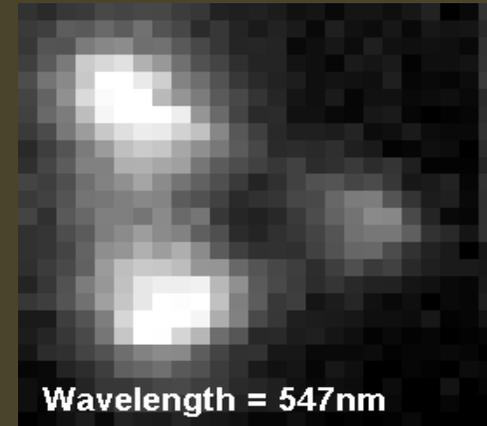
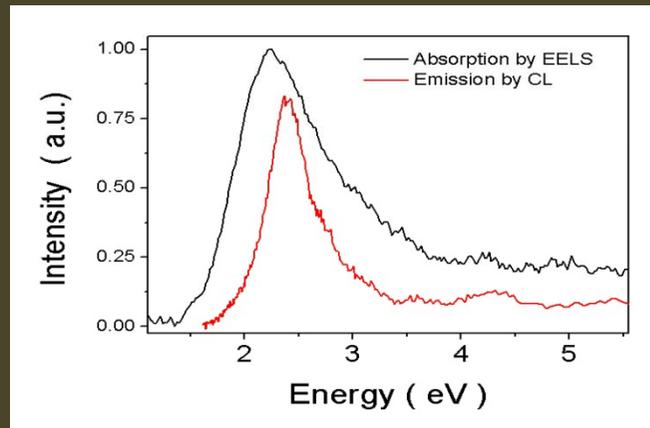
multi-detection: HADF+  
EELS + EIRE (CL)

first proof of principle for simultaneous EELS/EIRE

symmetry of the modes, modal  
decomposition?



Energy 2.2 eV



Wavelength = 547nm

**EELS**  
(radiative and non  
radiative modes)

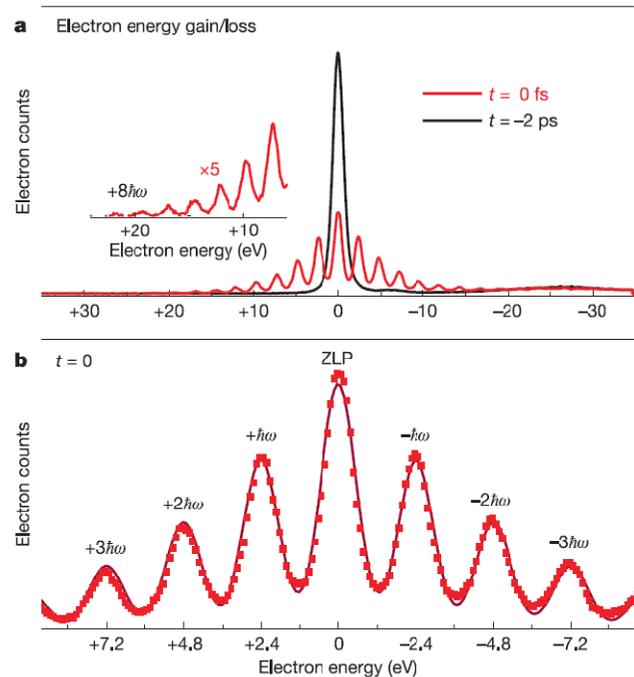
**CL**  
(only radiative  
modes)

No energy resolution limitation by the PSF detection system:  
**optical spectroscopy at a true nanometer scale**

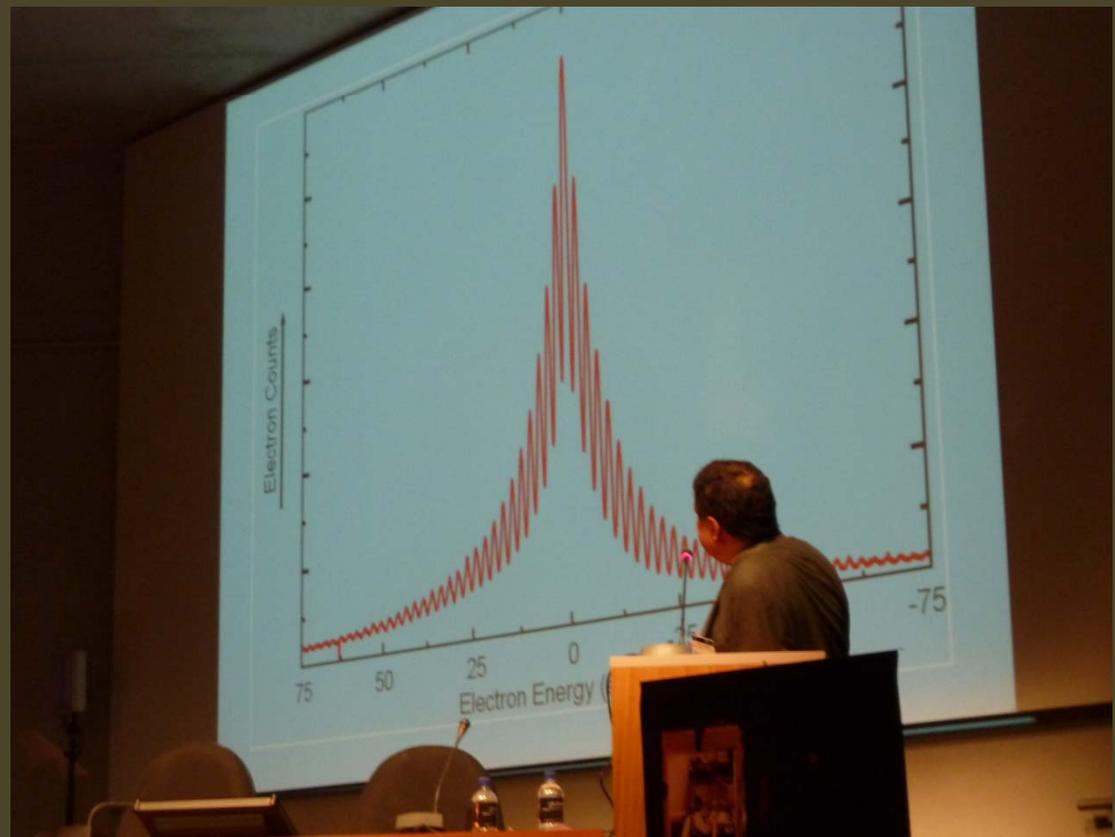
# Photon-induced near-field electron microscopy

Brett Barwick<sup>1</sup>, David J. Flannigan<sup>1</sup> & Ahmed H. Zewail<sup>1</sup>

Nature, 17 december 2009

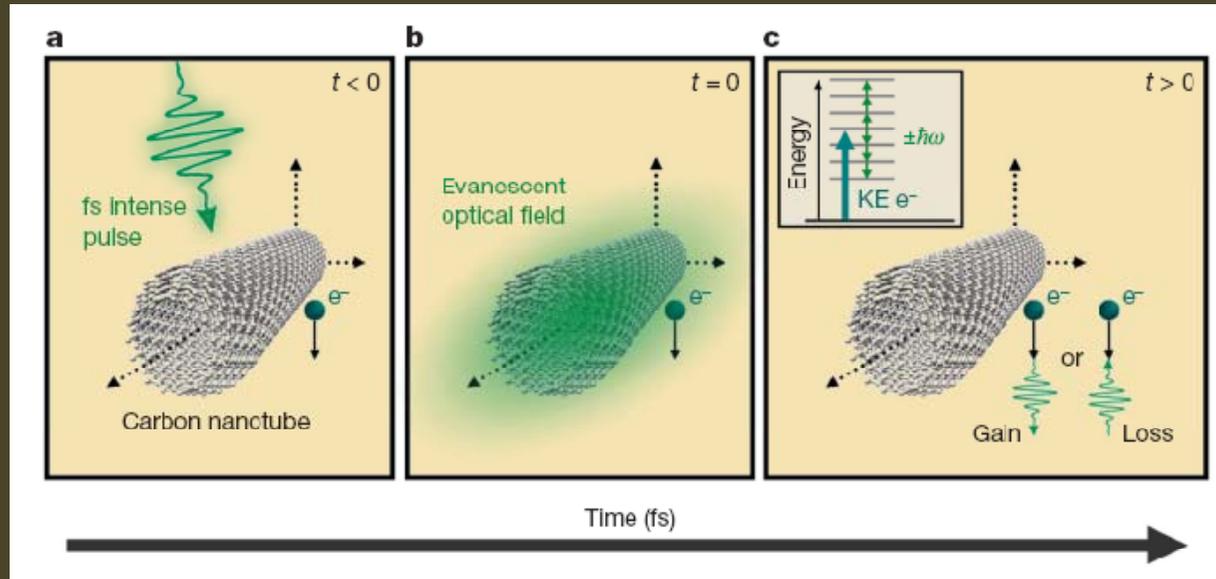


**Figure 1 | Electron energy spectra of carbon nanotubes irradiated with an intense fs laser pulse at two different delay times.** **a**, The zero-loss peak (ZLP) of the 200 keV electrons (black curve) taken when the electron packet arrives before the femtosecond pulse; in this spectrum only the plasmon peaks are present (see text). The energy spectrum at coincidence of the two pulses ( $t = 0$  fs; red curve) displays the multiple quanta of photon absorption/emission. Inset, the positive energy gain region multiplied by 5 for the  $t = 0$  spectrum, indicating that absorption of at least eight quanta of photon energy can be observed at maximum spatiotemporal overlap. **b**, Magnified view of the electron energy spectrum obtained at  $t = 0$ . The energy is given in reference to the loss/gain of photon quanta by the electrons with respect to the zero-loss energy.



and now?

With synchronised light injection (cf Zewail's group at UCLA)



New spectroscopies synchronizing electrons and photons (injecting light)

- (i) electron energy-GAIN spectroscopy
- (ii) dynamics of excited states

Stephen J. Pennycook  
Peter D. Nellist  
*Editors*

# Scanning Transmission Electron Microscopy

Imaging and Analysis

 Springer

**The most  
recent  
textbook on  
the market...**

**MRS Bulletin, January 2012**  
**on**  
**“Spectroscopic Imaging in Electron Microscopy”**

**Eds. S. Pennycook & C. Colliex**

**Invited contributions :**

**G. Botton, McMaster, Canada**

**M. Varela et al. ORNL, USA and Madrid, Spain**

**M. Kociak, Orsay, France & J. Garcia de Abajo, Madrid, Spain**

**K. Suenaga et al. AIST, Japan**

**L.J. Allen et al. Melbourne, Australia**

**M. Aronova & R.D. Leapman, NIH, USA**



Laboratoire de Physique des Solides • UMR 8502 Université Paris sud bât 510 • 91405 Orsay cedex



## The Orsay team enabling the future (june 2011)



<http://www.lps.u-psud.fr/stemplps>

**Thanks to all my colleagues at LPS Orsay**

**Guillaume Boudarham, Laura Bocher  
Nathalie Brun, Alexandre Gloter,  
Mathieu Kociak, Katia March,  
Stefano Mazzucco, Claudie Mory,  
Odile Stéphan, Marcel Tencé,  
Almudena Torres-Pardo, Mike Walls,  
Luis Zagonel and Alberto Zobelli  
from LPS Orsay, France**

**Thanks to CNRS CNRS and to EC funded programs EU  
SPANS et ESTEEM and to all our partners who have  
submitted scientific issues to solve and suited specimens**

**Thank you very much for your attention**

